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Cryo-EM Workshop@NUS

General Cryo-EM References

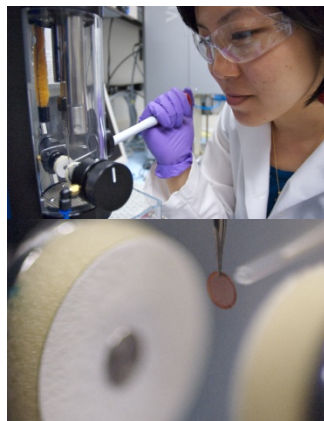
- Glaeser, R. M., Downing, K, DeRosier, D., Chiu, W. and Frank, J. (2007) *Electron Crystallography of Biological Macromolecules*, Oxford University Press.
- [Chang J](#), [Liu X](#), [Rochat RH](#), [Baker ML](#), [Chiu W](#). (2012). Reconstructing virus structures from nanometer to near-atomic resolutions with cryo-electron microscopy and tomography. *[Adv Exp Med Biol](#)*. **726**:49-90.
- Jensen, G. (2010) [Methods in Enzymology Volume 481](#). Many review papers

Pipeline in Single Particle Cryo-EM

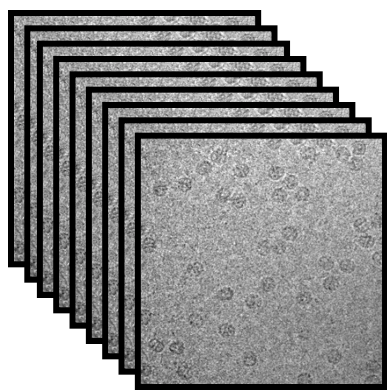
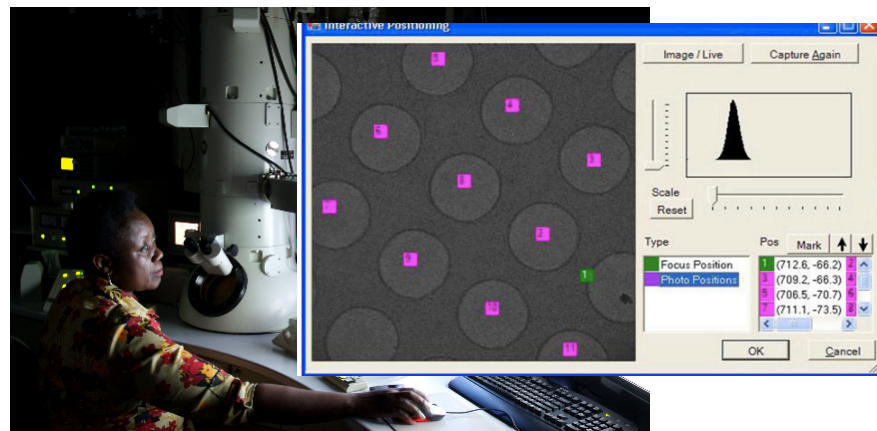
Biochemical
Preparation



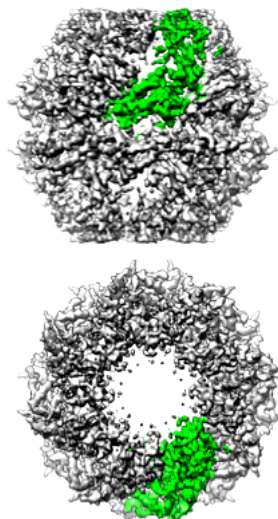
Cryo-EM Sample
Preparation



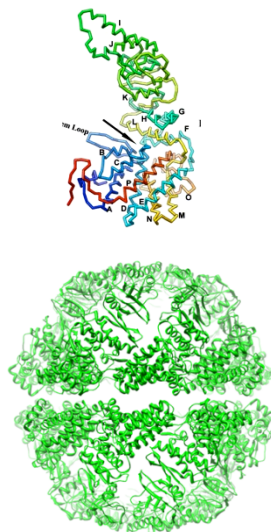
High Resolution Automated Data Collection
JADAS



Data Archiving & Processing
EMEN



3D Reconstruction
EMAN



Model Building & Validation
Gorgon

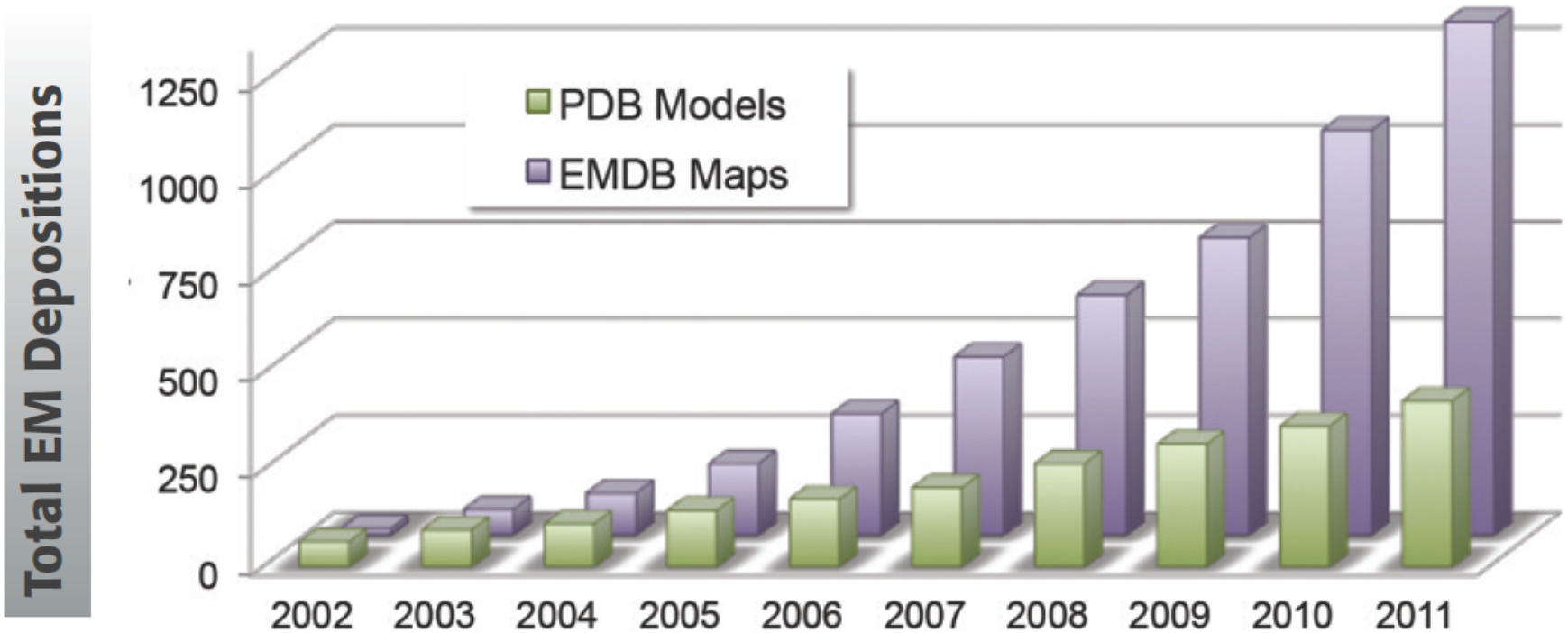
WORLDWIDE
wwPDB
PROTEIN DATA BANK

Structure
Deposition

Why CryoEM?

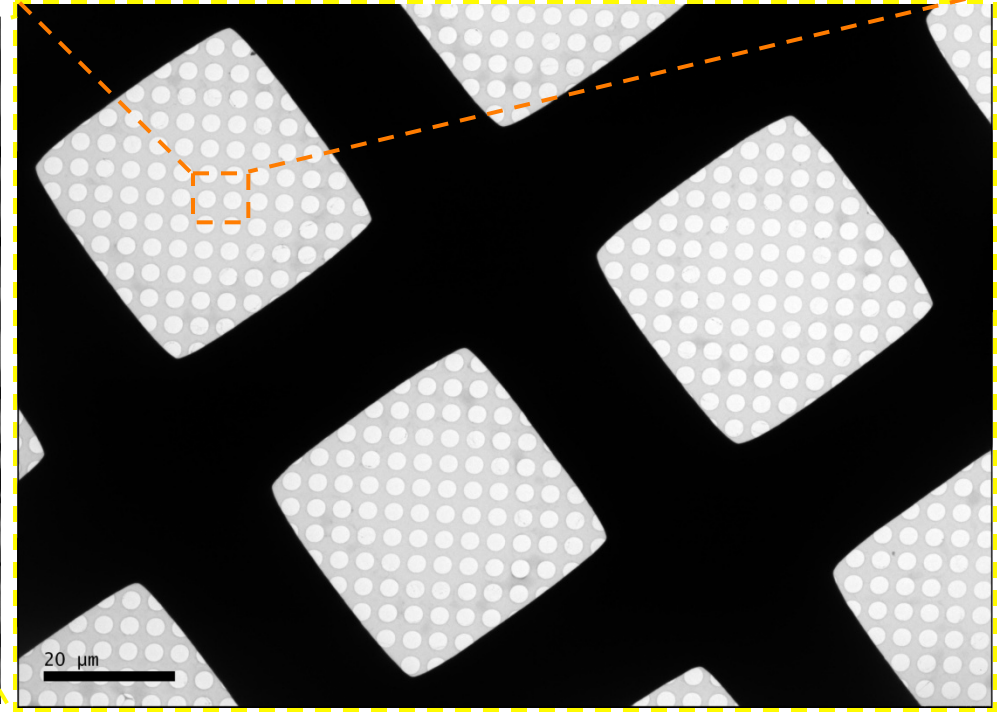
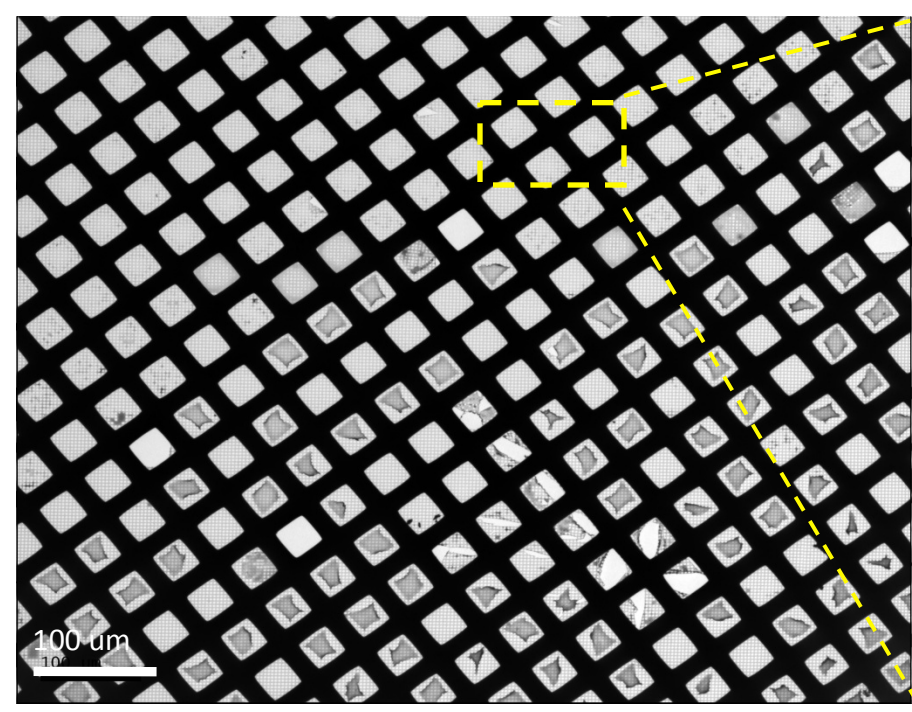
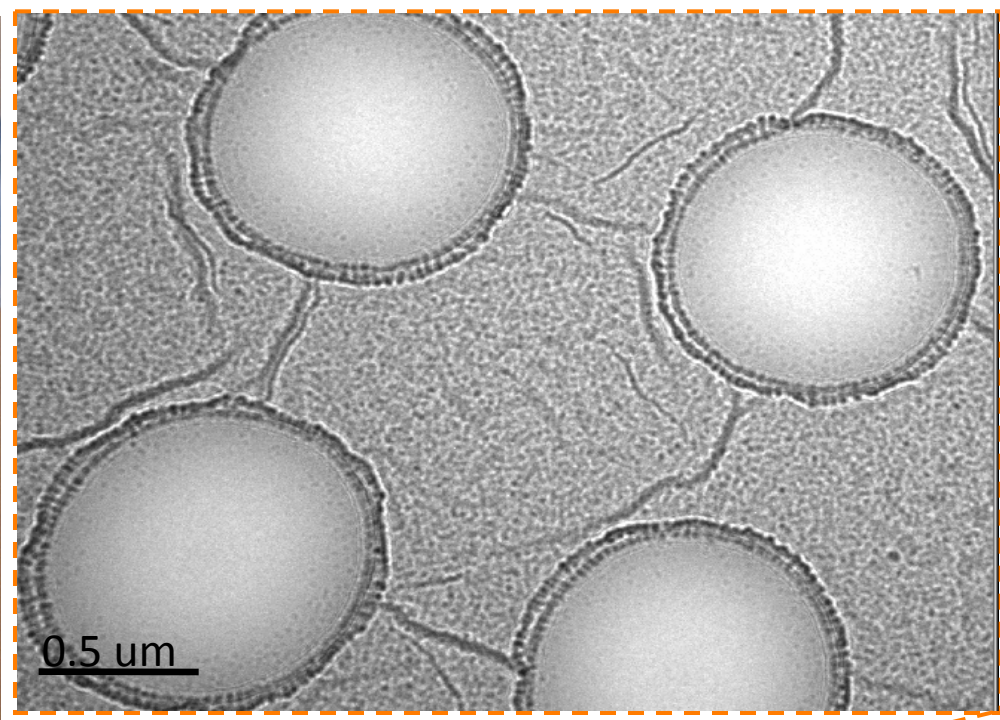
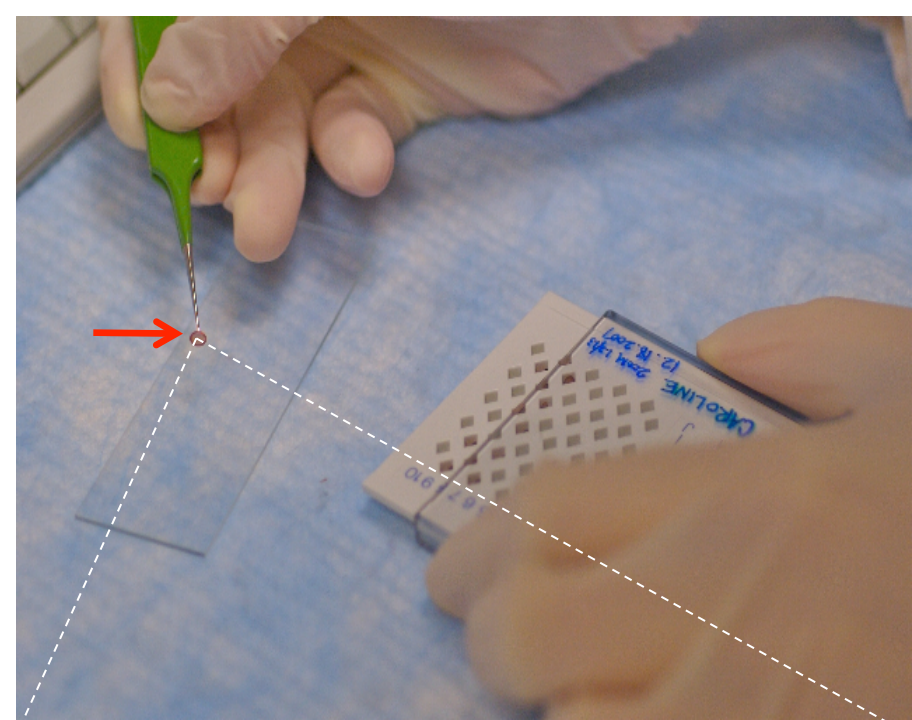
- Can determine structures at different chemical or biological conformation states
- Can work with large complex of mixed/dynamic conformations
- Can determine Structure that cannot be tackled readily by NMR or crystallography
- Need only low concentration (<1mg/ml) in less than 100 μ l sample
- Resolution can be reached to ~ 3.5 Å in favorable cases

Growth of EM Entries



Cryo-Specimen Preparation

- Dubochet, J., Adrian, M., Chang, J.J., Homo, J.C., Lepault, J., McDowell, A.W. & Schultz, P. (1988). *Q Rev Biophys* 21, pp. 129-228.
- Taylor, K.A., and Glaeser, R.M. (2008). Retrospective on the early development of cryoelectron microscopy of macromolecules and a prospective on opportunities for the future. *J Struct Biol* 163, 214-223.
- Megan J. Dobro, Linda A. Melanson, Grant J. Jensen, Alasdair W. McDowell (2010) Plunge Freezing for Electron Cryomicroscopy. *Methods in Enzymology* 481, 63-82.



Basic Requirements for Vitrification Apparatus

1. Ambient

- low humidity & proper electrical grounded

2. Blotting mechanism

- manual, pneumatic or electronic

3. Blotting chamber

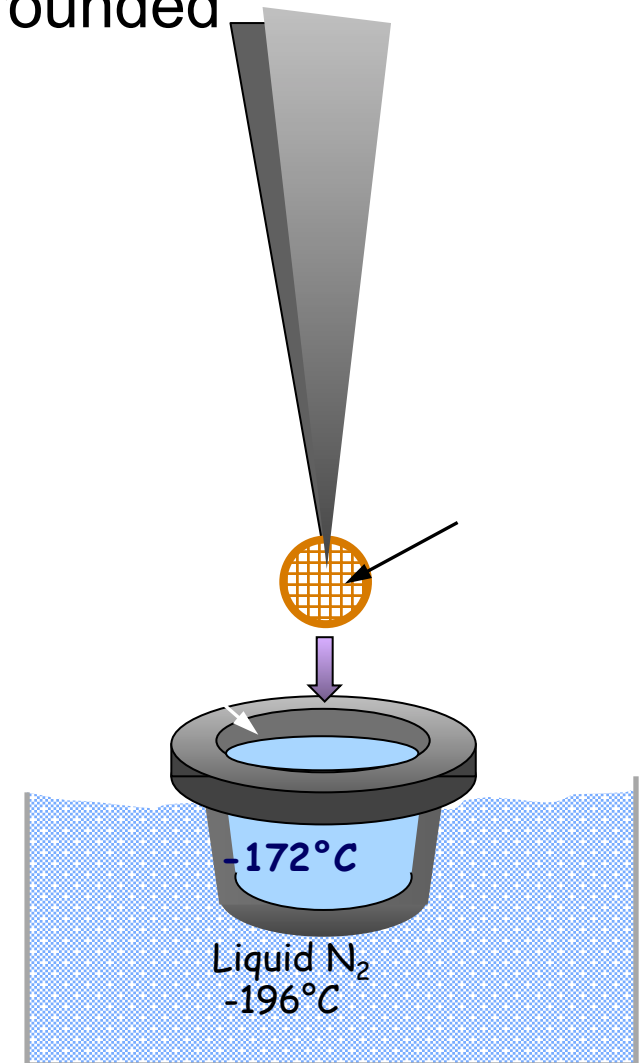
- high humidity

4. Plunging mechanism

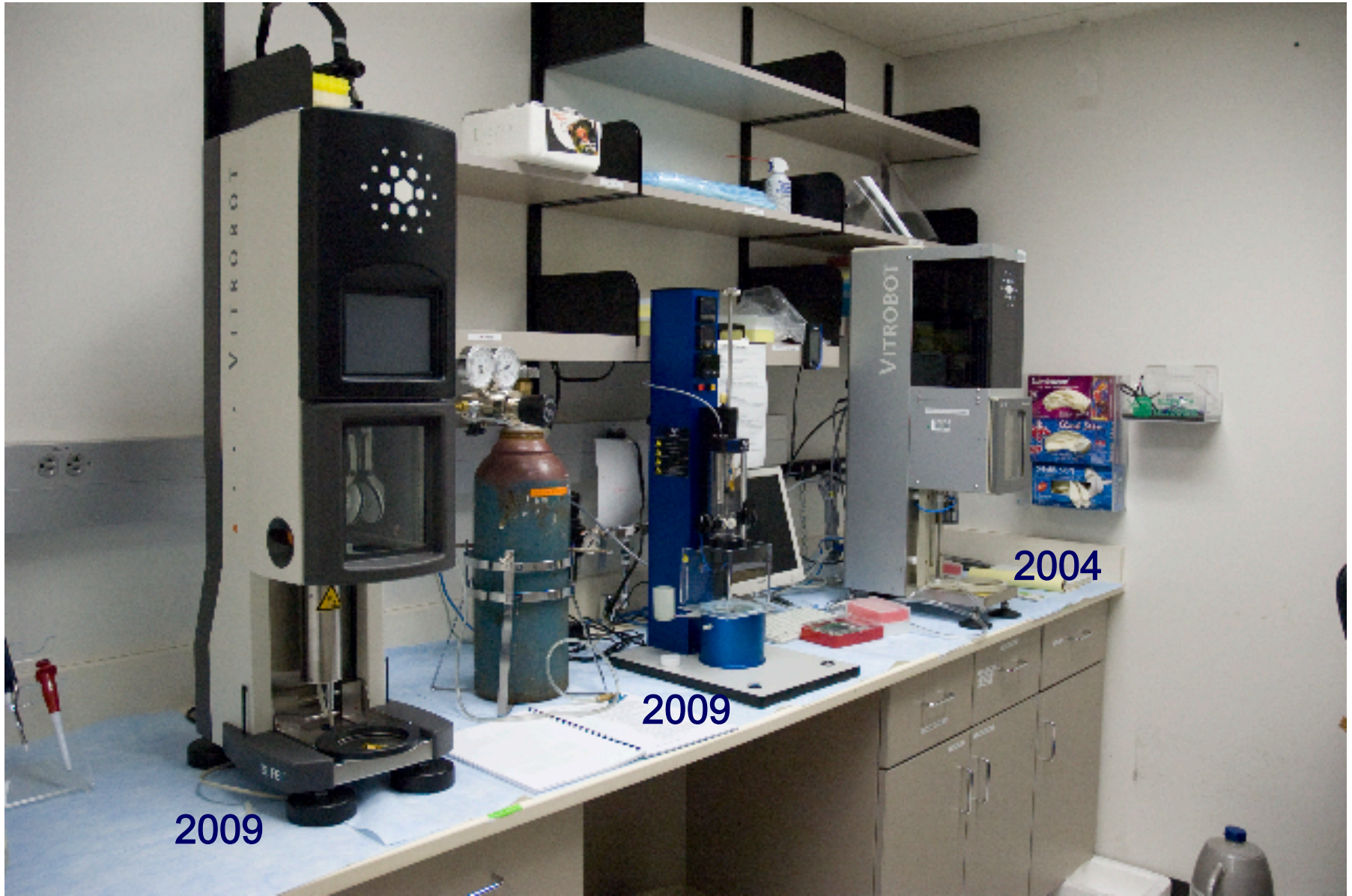
- high entrance velocity

5. Cryogen

- high cooling efficiency



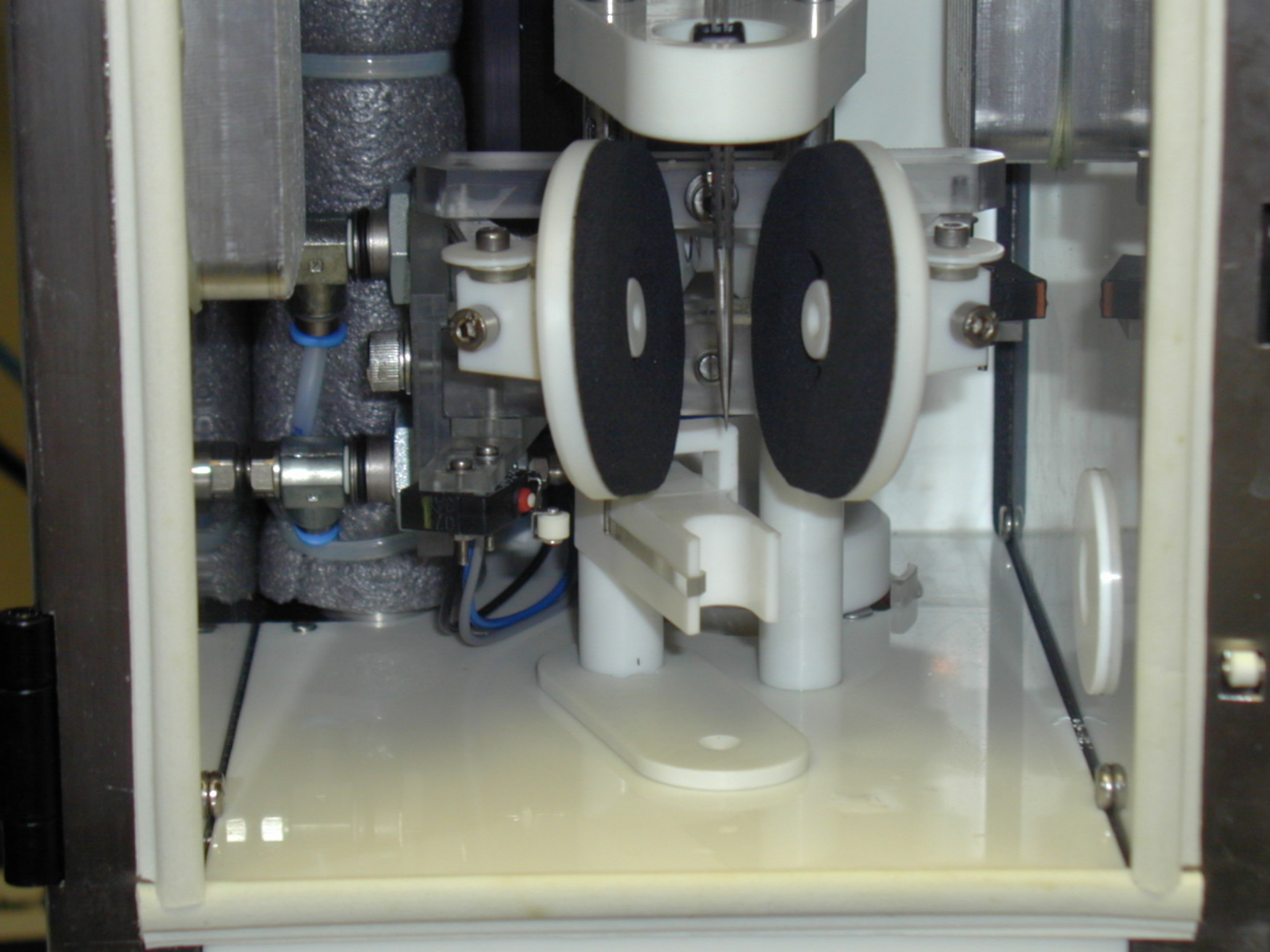
Cryo-Specimen Preparation

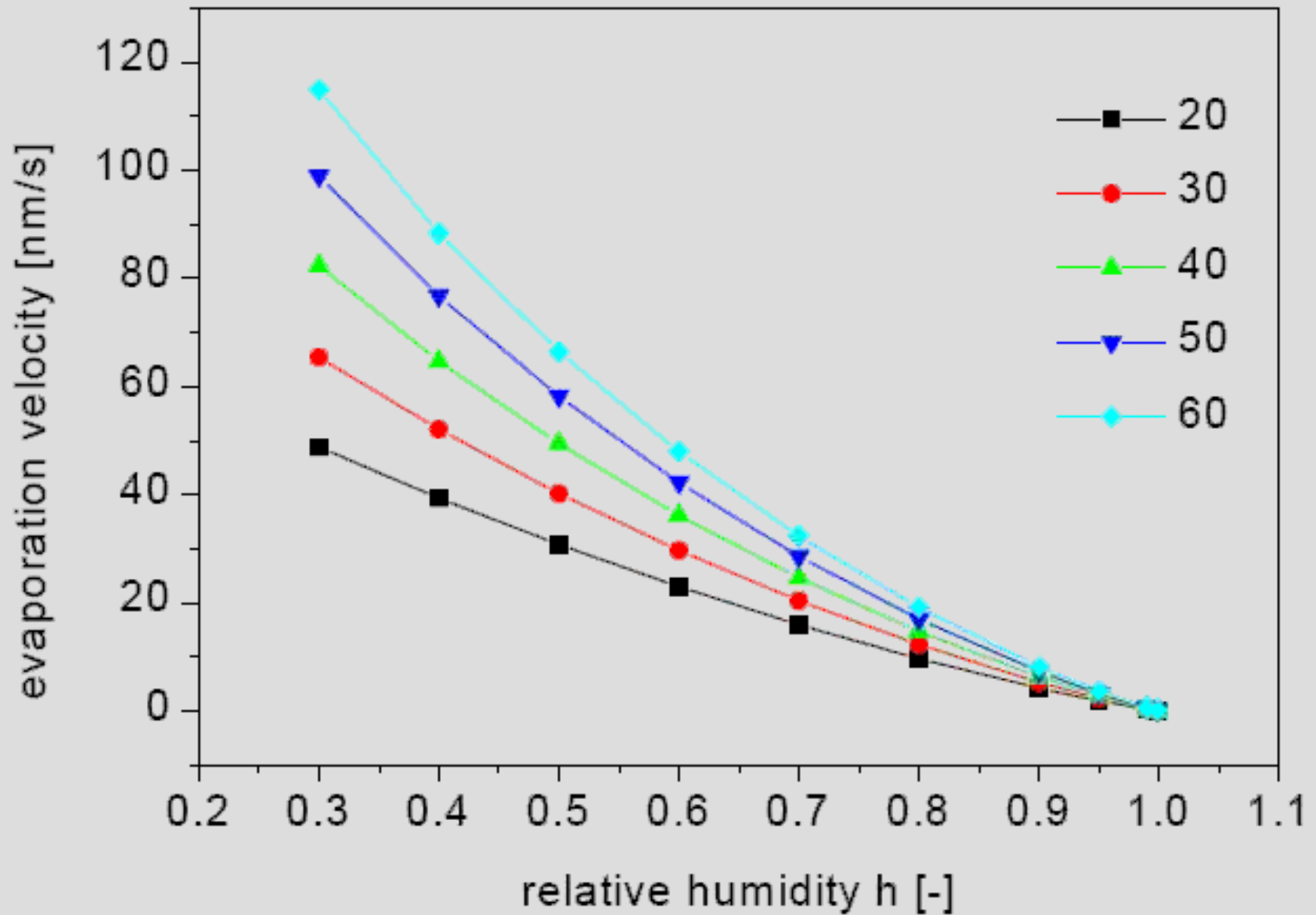


2009

2009

2004

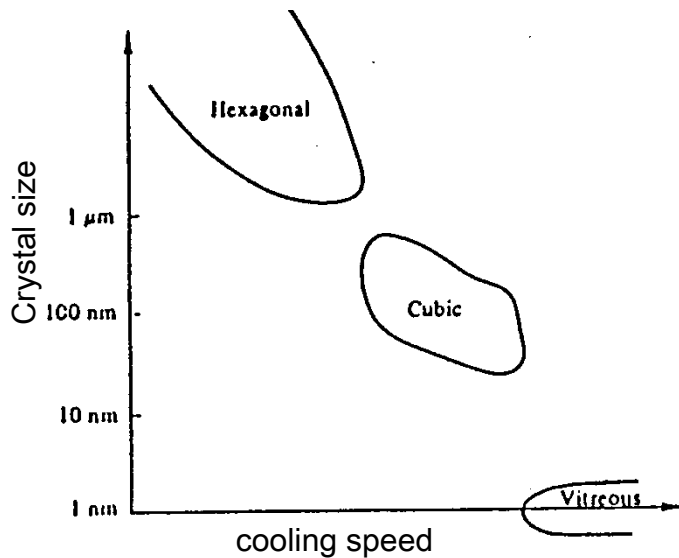




Courtesy Dr. Peter Frederik, University of Maastricht

Vitrification

Vitrification – immobilization of H₂O is achieved before its crystallization



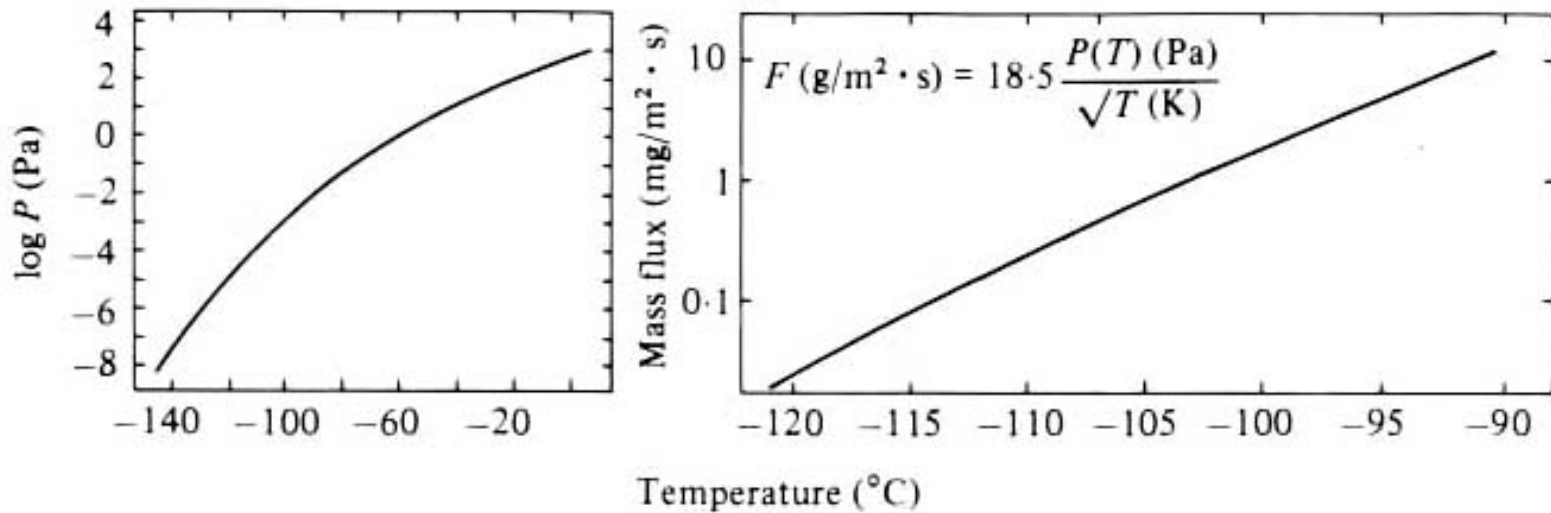
- rapid cooling rate
- small mass of specimen

For pure water:

cooling rate: 10^6 °C/sec (for 1 μm thick layer)

vitrification time: $t_v = 10^{-4}$ sec

Sublimation of ice in an electron microscope ?

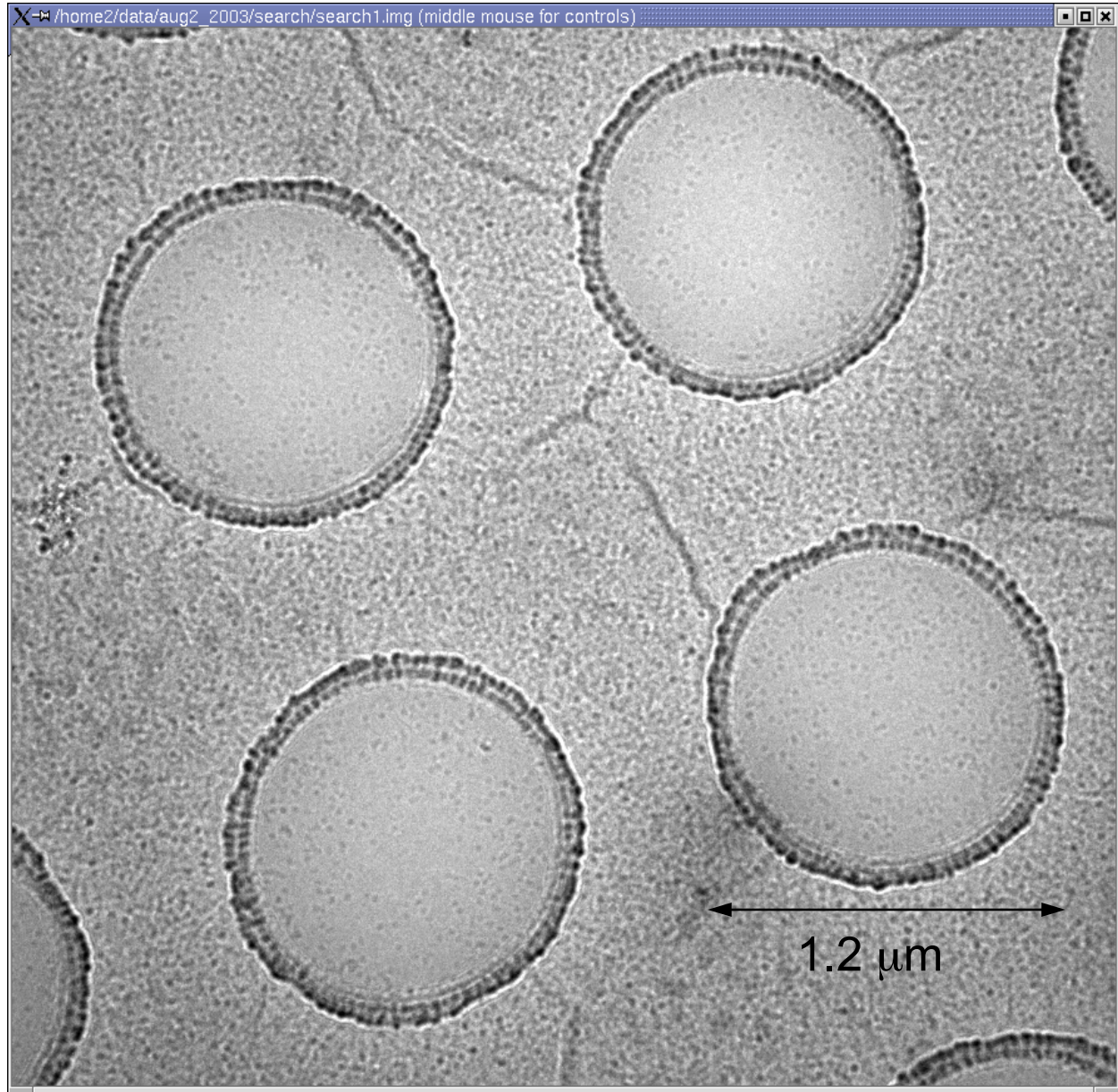


- (a) Vapour pressure P in Pa as function of the temperature in $^{\circ}\text{C}$.
(133Pa = 1 Torr; 10^5 Pa = 1 bar = 0.987 atm)
- (b) Sublimation of ice in perfect vacuum as a function of the temperature in $^{\circ}\text{C}$.
(1 mg/m^2 corresponds to 1 nm thickness at a density of $1 \text{ g}/\text{cm}^3$).

**** Sublimation of vitreous ice is very small at $T \leq T_v$**

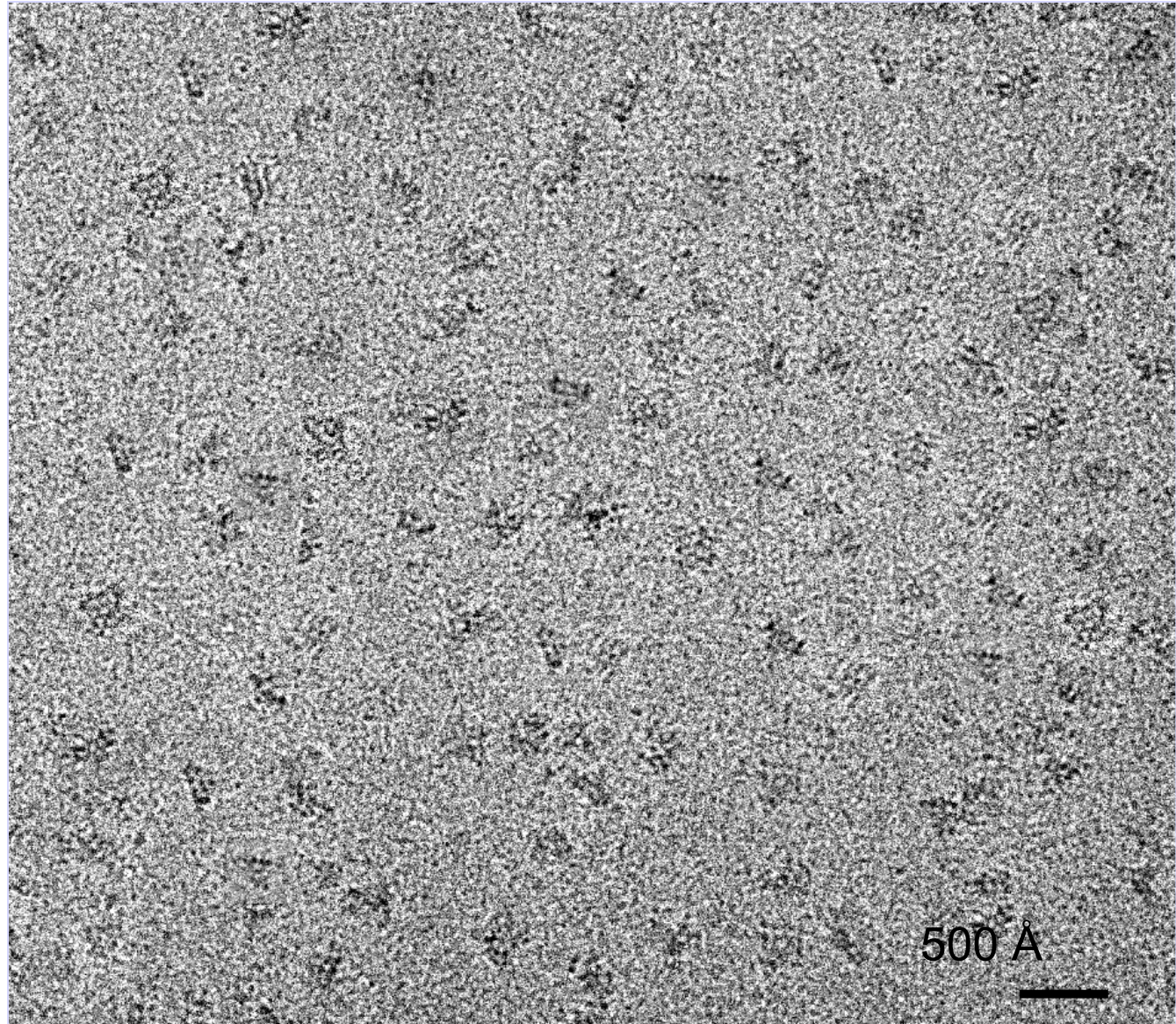
Vitrified Sample

in 20 mM Mops (pH 7.4), 300 mM KCl, 1 mM DTT, 0.4% CHAPS, 5% sucrose



Courtesy of
Dr. I Serysheva

200 kV image of ice-embedded Ion Channel



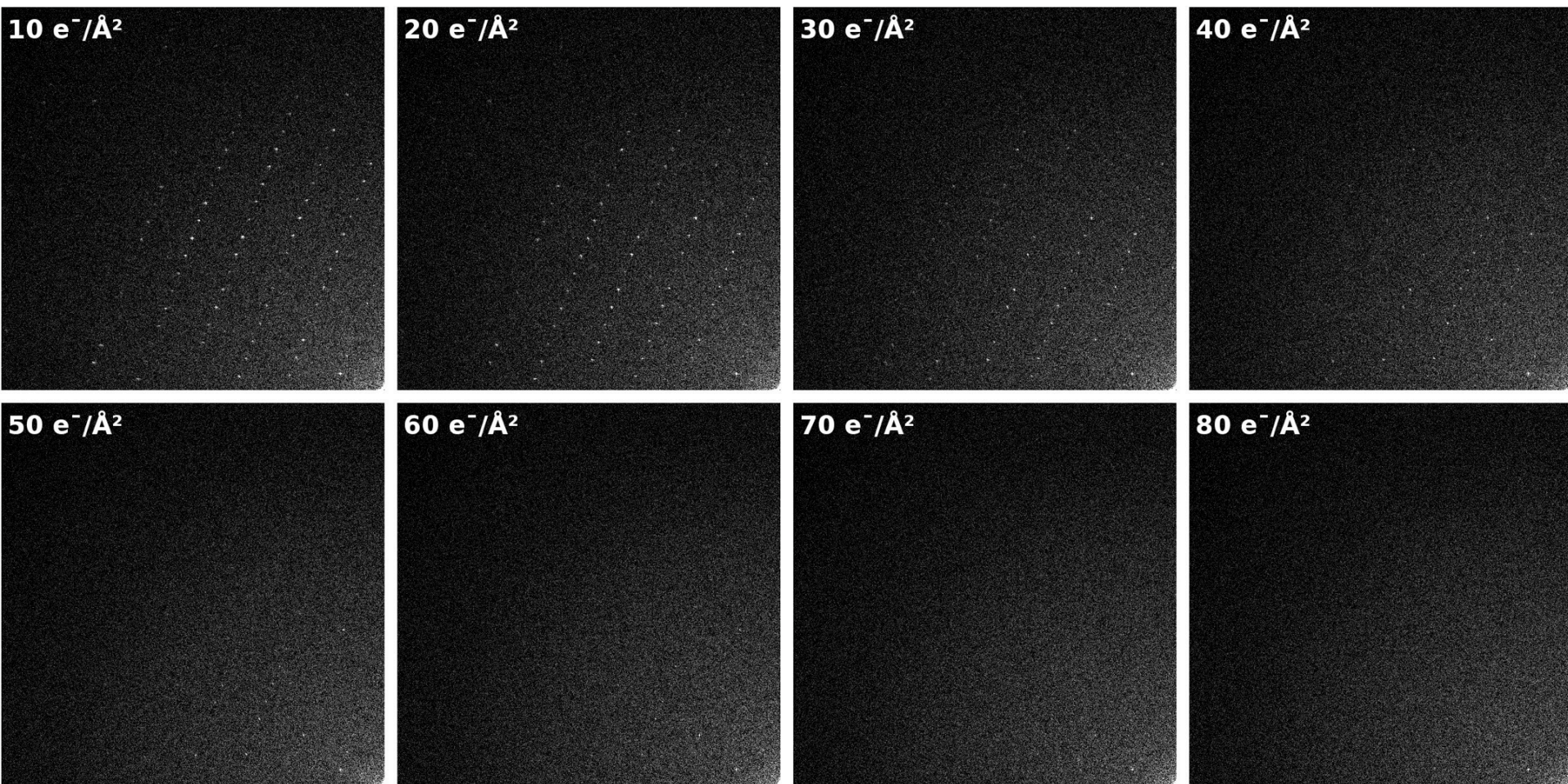
Courtesy of
Dr. I Serysheva

Radiation Damage Assessment of Protein Crystals

Record a series of 9-10 electron images or electron diffraction patterns from a single thin protein crystal (catalase crystal)

Measure quantitatively the fading of the diffraction spot intensities as a function of cumulative exposure (also known as dose)

Radiation Damage Studies of Ice Embedded Catalase Crystal

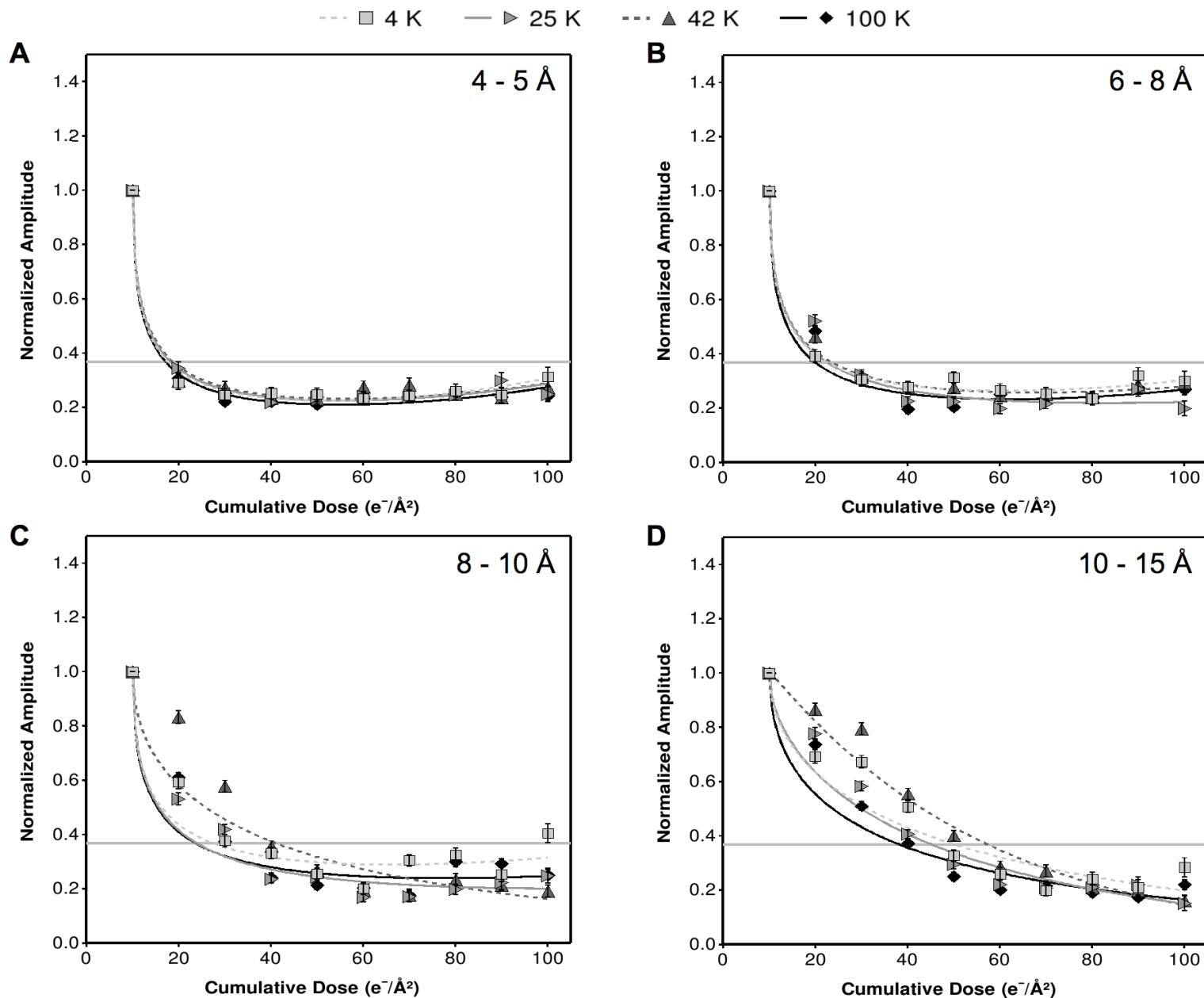


Quantification of Damage

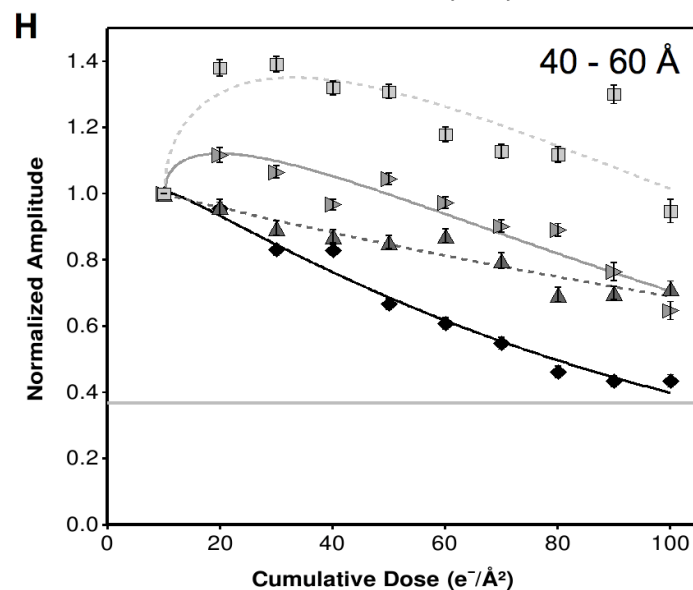
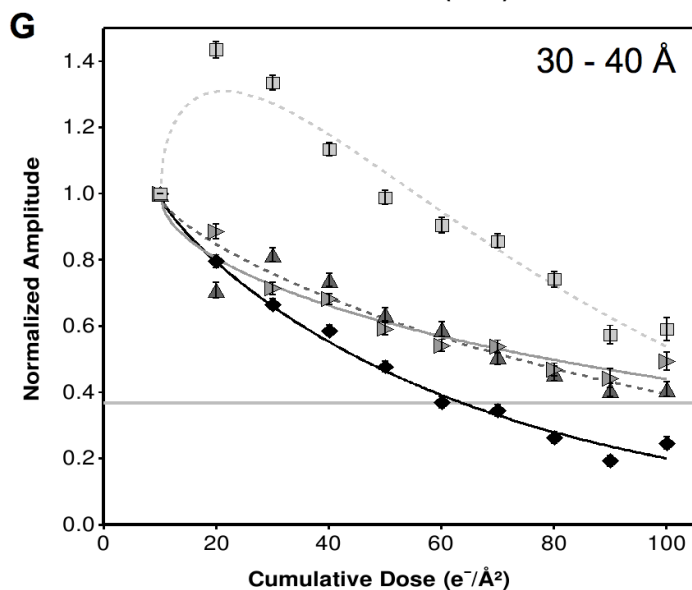
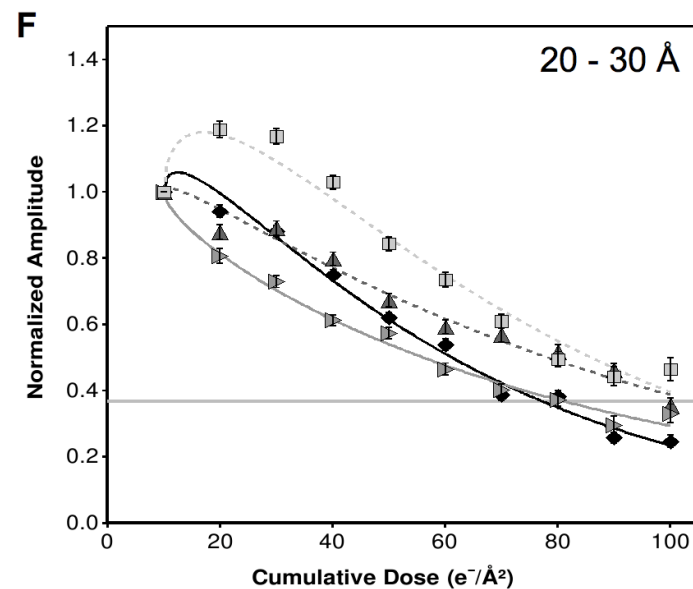
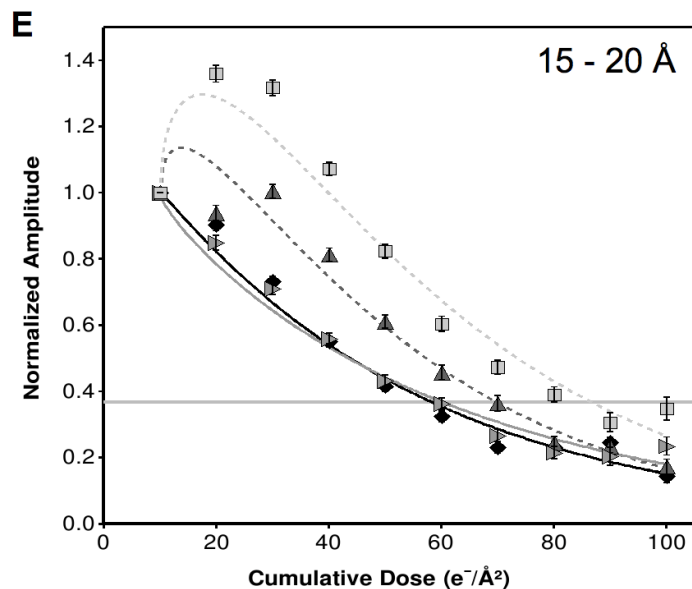
N_e (1/e) decay dose

Dissimilarity factor

Fading of Fourier Amplitudes at different temperatures



Fading of Fourier Amplitudes at different temperatures



--- □ 4 K — ▴ 25 K ... ▲ 42 K — ◆ 100 K

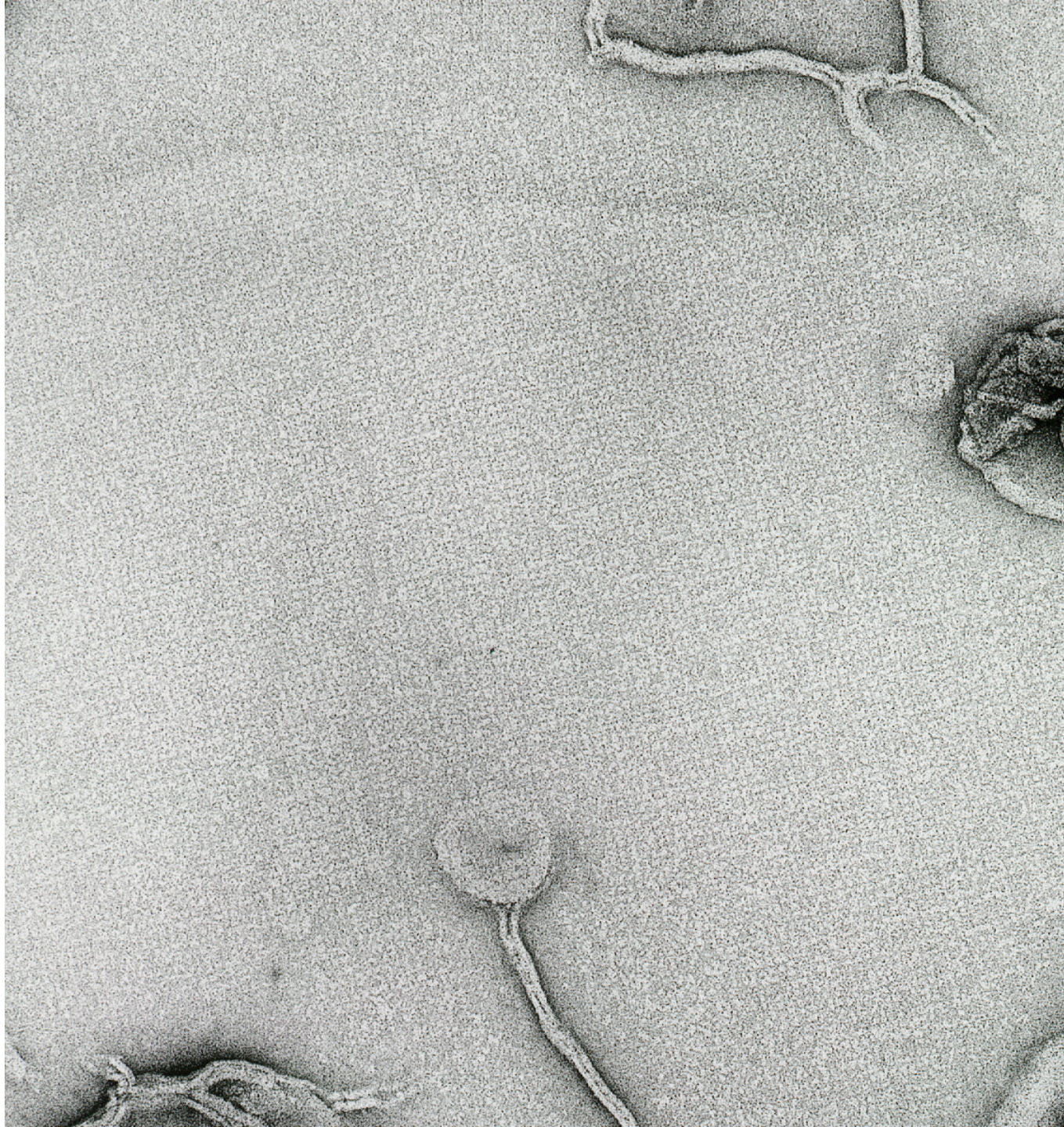
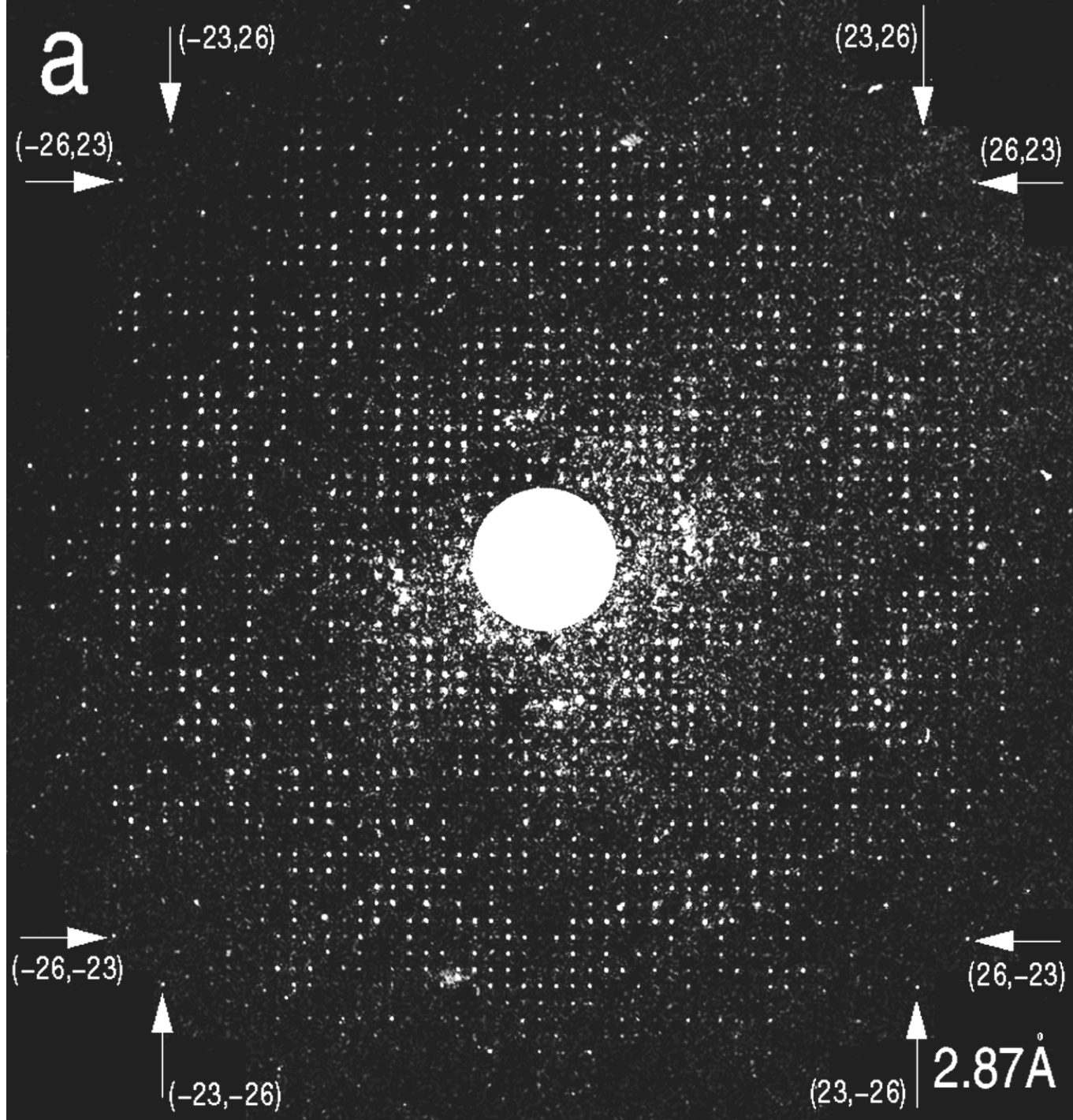


Image of a
2D protein
crystal

G Ren

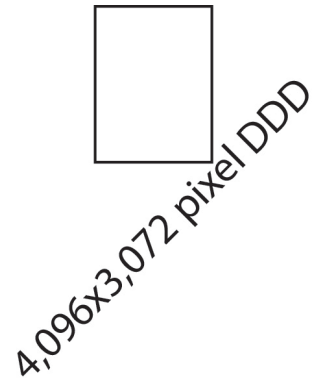
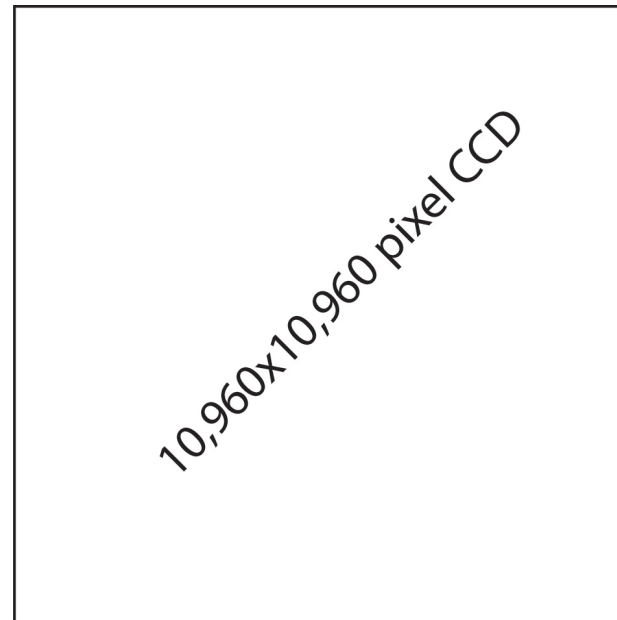


Electron
Diffraction
Pattern
of a Protein
2-D
Crystal

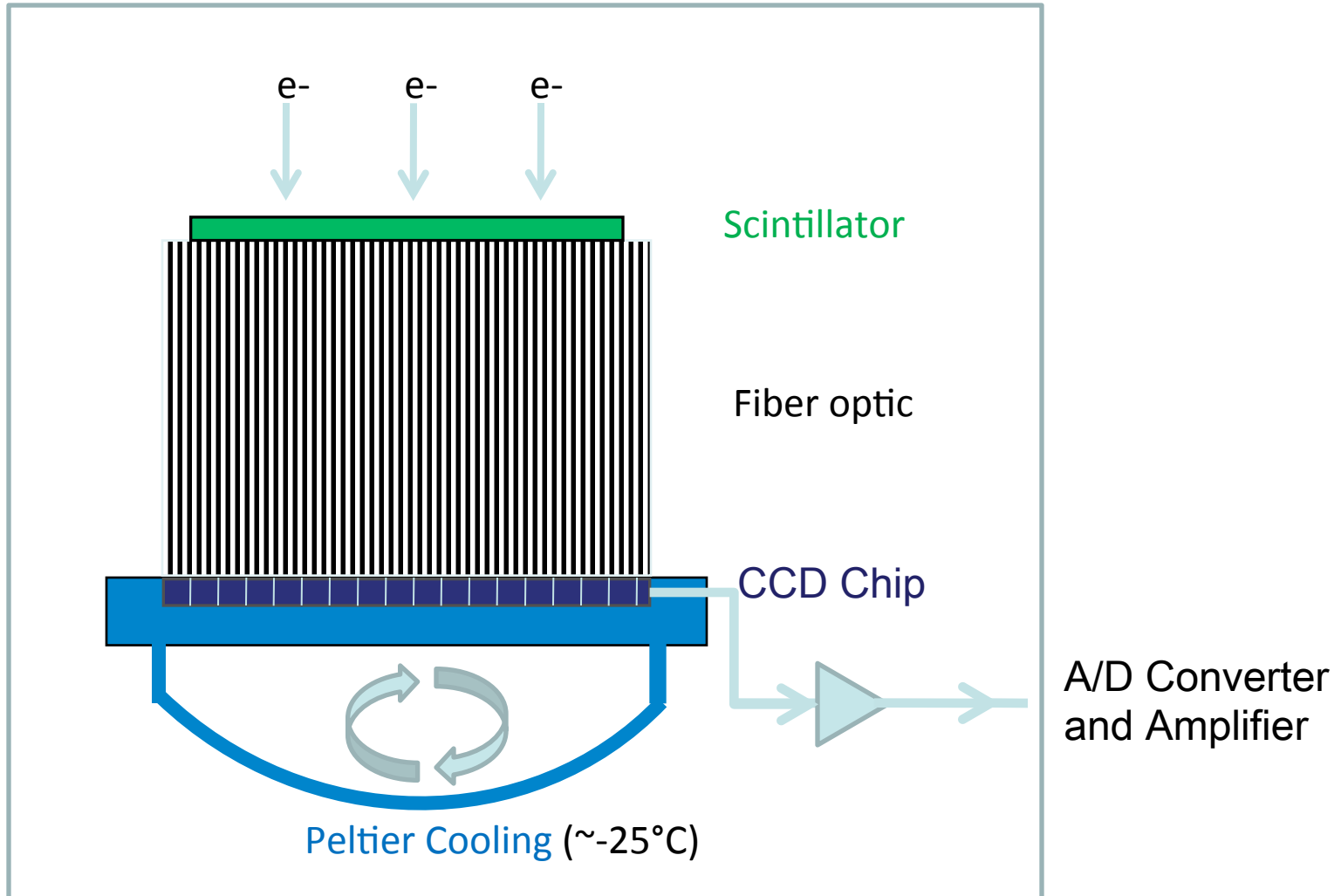
Ren & Mitra

Detector Physical Sizes

- 4x4 K CCD (16 megapixels with 15 μm pixel size)
- 10x10 K CCD (111 megapixel with 9 μm pixel size)
- 3x4 K DDD (12.6 megapixel with 6 μm pixel size)
- Photographic film



TEM CCD Architecture



Field of View and Microscope Ports

Magnification

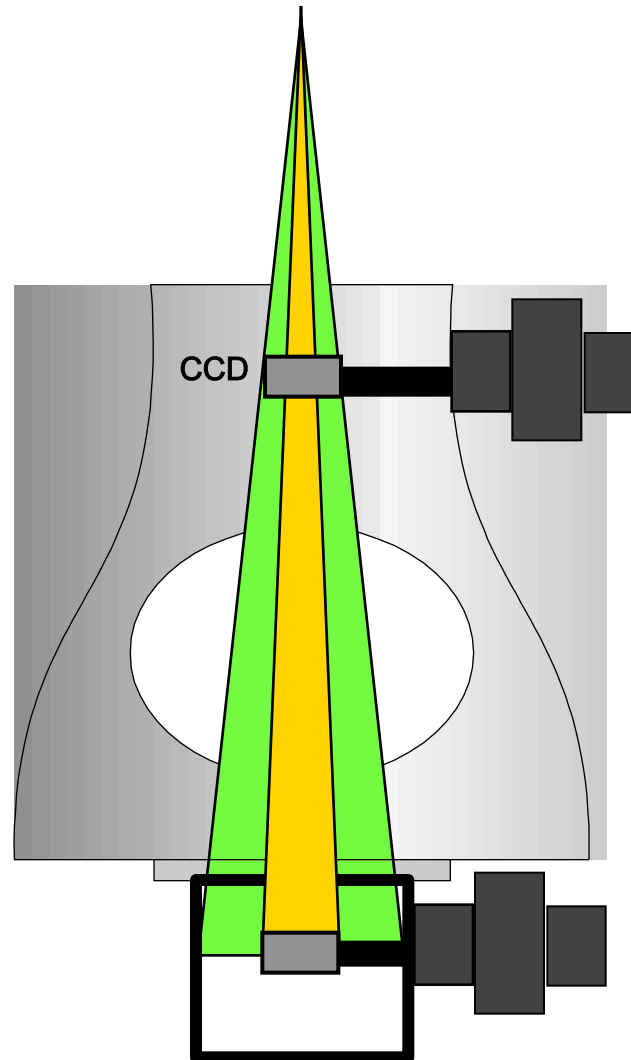
Field of view

**35 mm Port
(Small)**

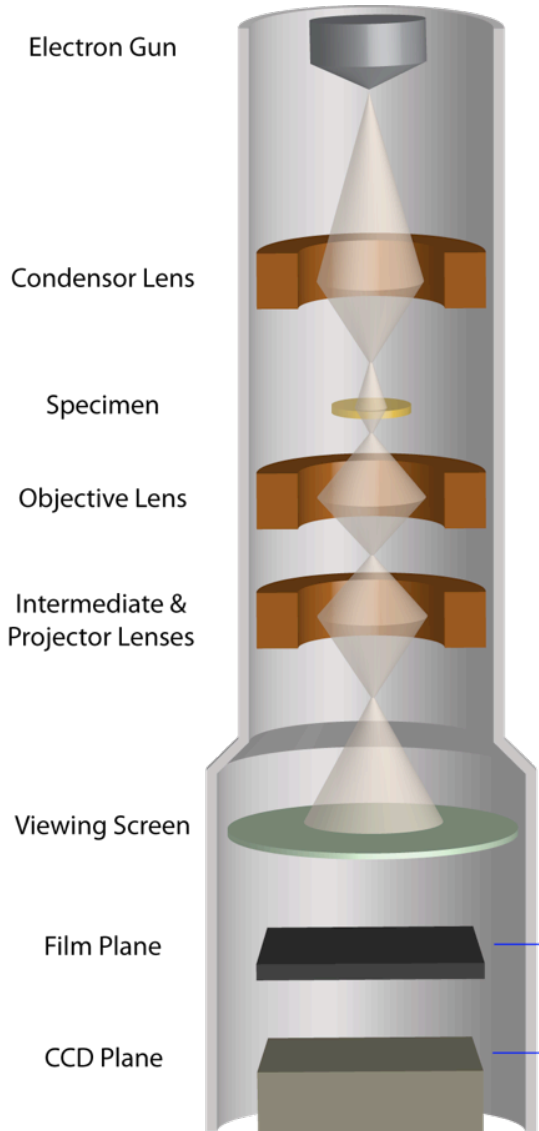
**35 mm Port
(Large)**

**Bottom
(Large)**

**Bottom
(Small)**



Magnification Factor

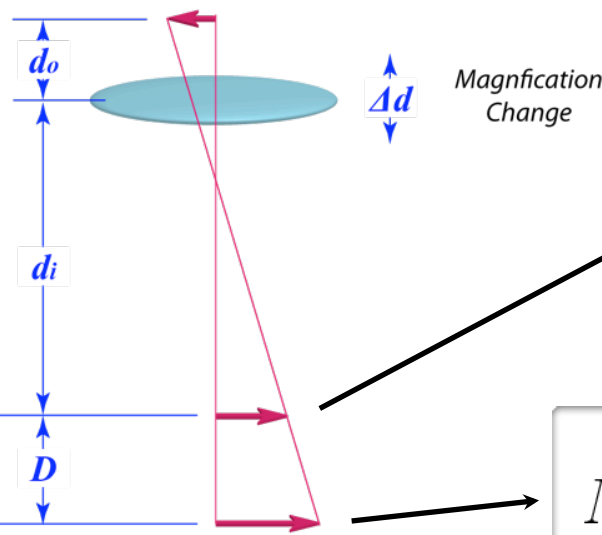


$$\frac{M_{\text{ccd}}}{M_{\text{film}}} = \frac{d_i + D + \Delta d}{d_i + \Delta d} = 1 + \frac{D}{d_i + \Delta d}$$

Depends on MAG

*Behaves as
Single
Magnifying
Lens*

SA Plane



$$M_{\text{film}} = \frac{d_i + \Delta d}{d_o - \Delta d}$$

$$M_{\text{ccd}} = \frac{d_i + D + \Delta d}{d_o - \Delta d}$$

Δd varies in different magnification of the scope

- Resolution: Simply, the ability to distinguish contrast (usually fine detail.) Often expressed in conjunction with MTF.
- Sensitivity: The level of (incoming) signal required to produce an intensity (output) change.
- Point Spread Function (PSF): Distribution of photons from incoming electron (i.e., cloud due to random motion of electron.)
- Dynamic Range: Simply, the range of values that can be distinguished between a maximum level and zero (noise.) Driven by combination of full well (affected by pixel size) and noise baseline with no exposure. Can be increased with binning.
- DQE (Detection Quantum Efficiency): Best “overall” measure of a camera’s ability to transfer signal accounting for noise from sensor to output. Expressed over a range of spatial frequencies. Noise-free image $DQE = 1$.

Resolution (d) in object (real) space and Frequency (s) in Fourier (diffraction) space

Object space resolution: d (nm)

Total sampling points in an image: N

Fourier space sampling distance: Δs (1/nm) = $1/(Nd)$

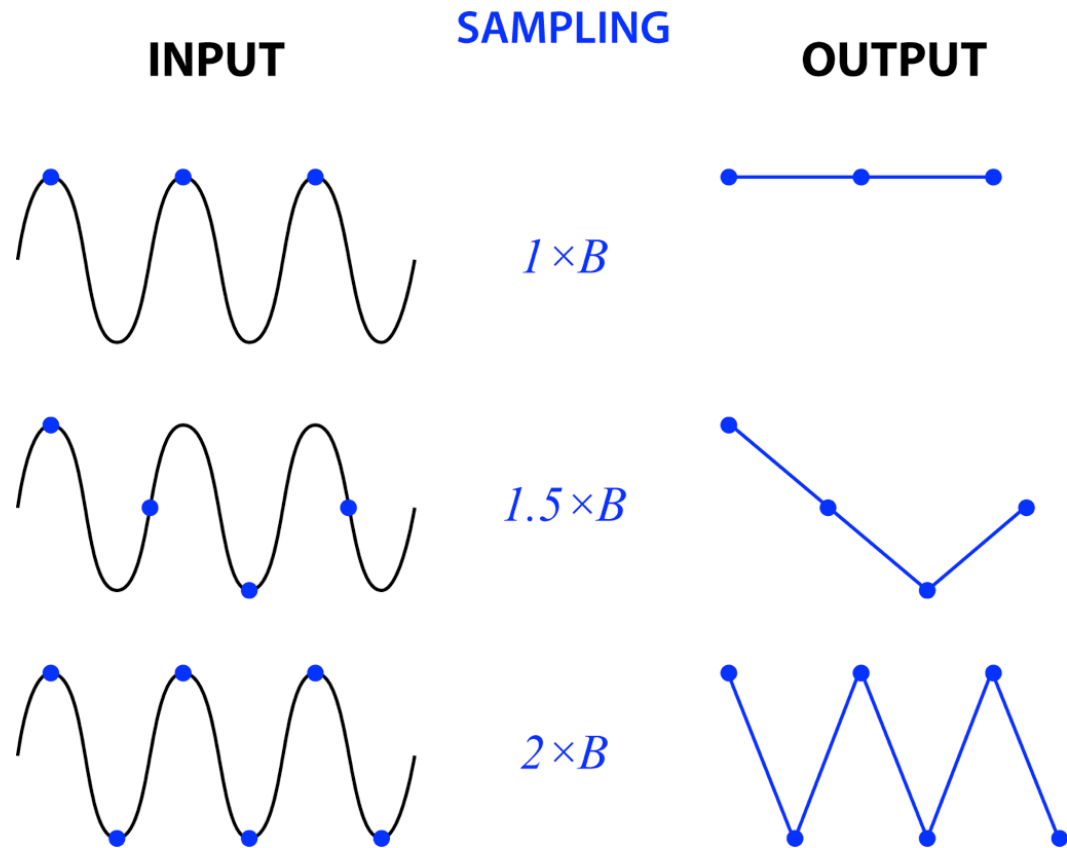
Maximum frequency (Nyquist) in Fourier space

$$s_{\max} = \frac{1}{2} d$$

Nyquist Frequency

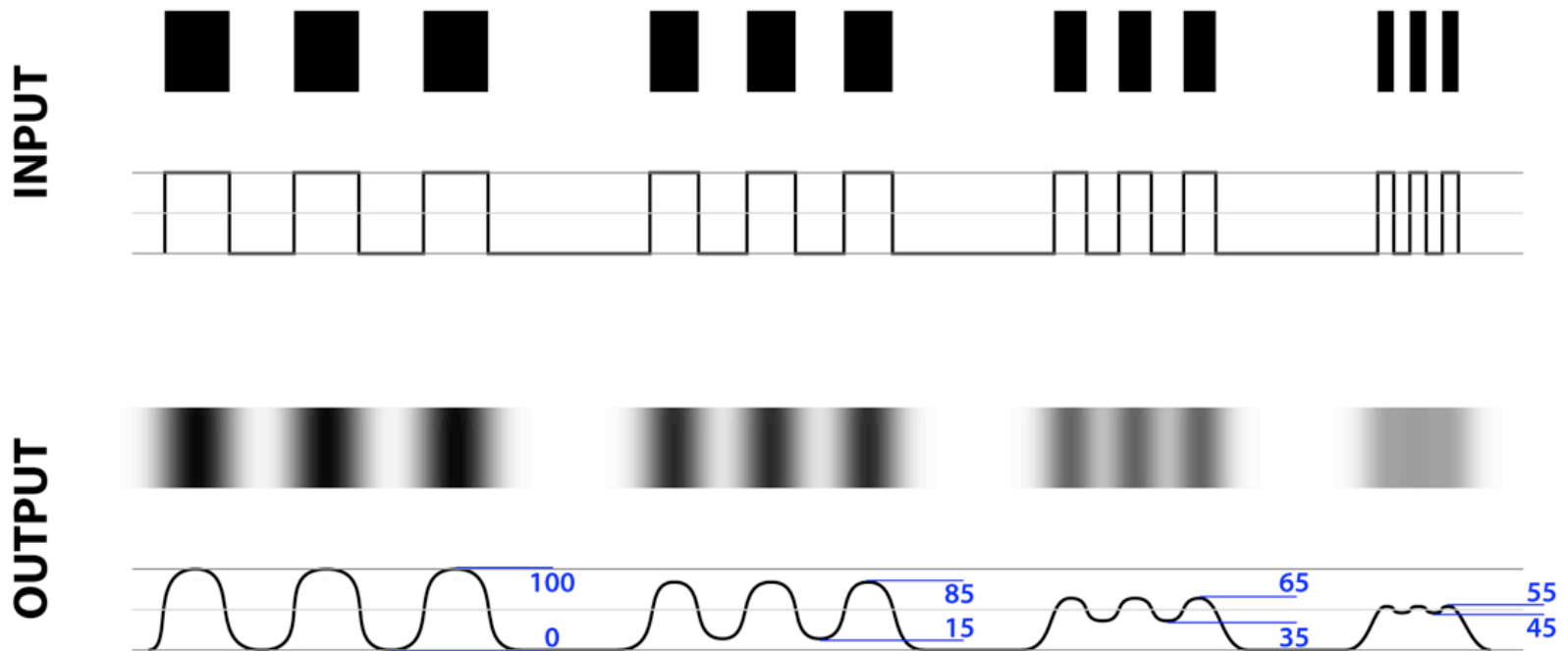
Nyquist-Shannon Sampling Theorem

If a signal contains no information at frequencies higher than $S_{\max} = B$, then it can be reconstructed by sampling with a frequency of $2S_{\max}$ or higher



Modulation Transfer a Function of Frequency

$$M = (I_{\max} - I_{\min}) / (I_{\max} + I_{\min})$$



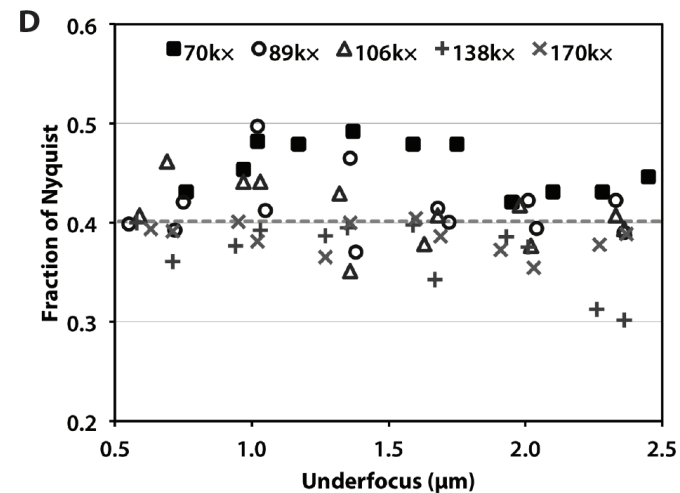
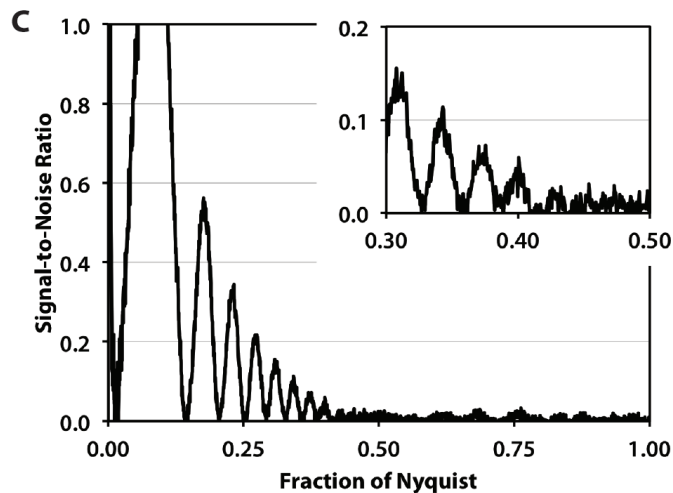
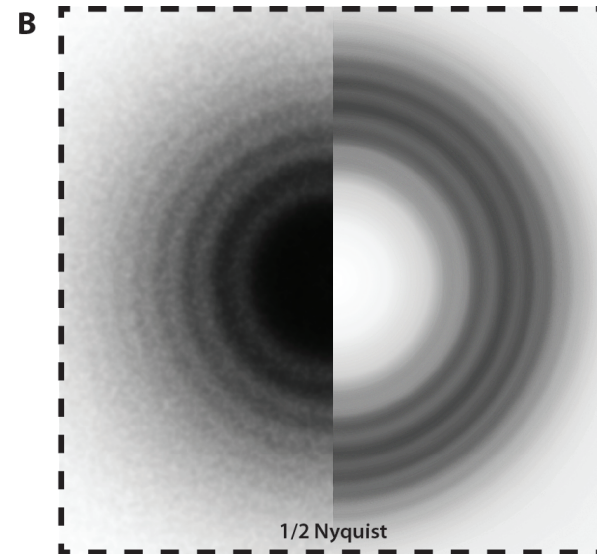
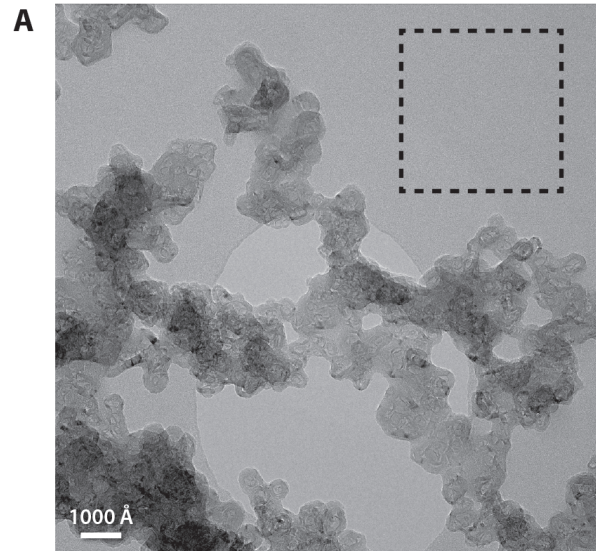
$M=1$

$M=0.7$

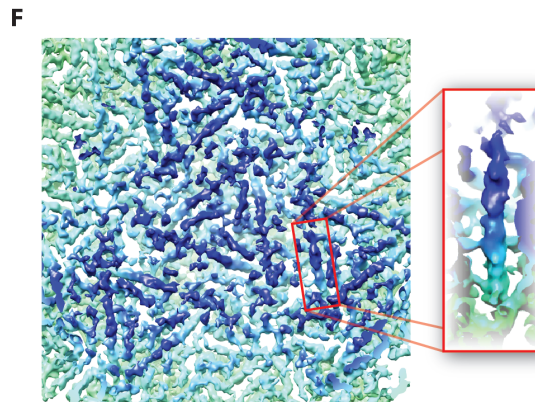
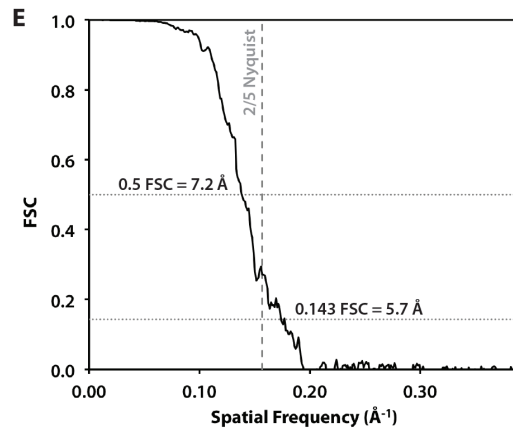
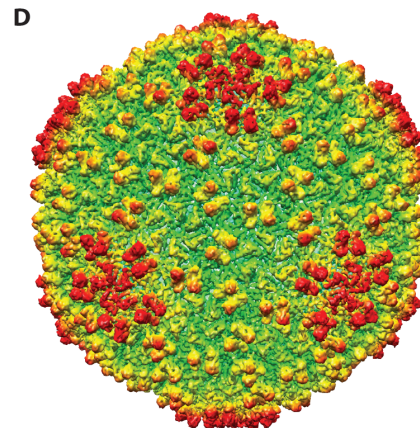
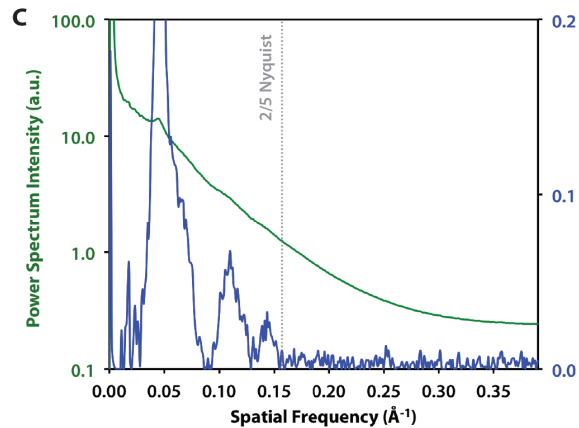
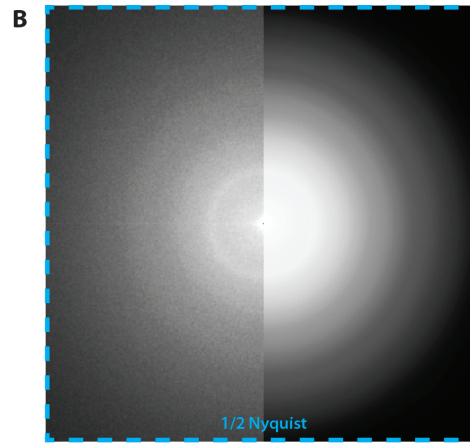
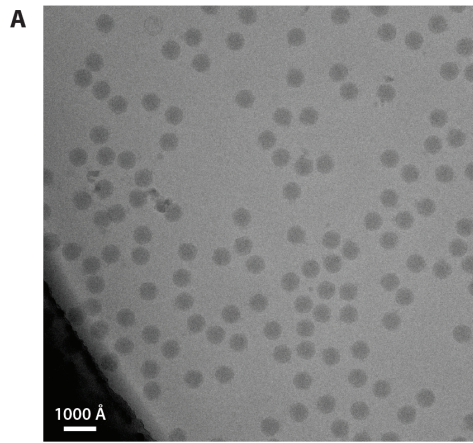
$M=0.3$

$M=0.1$

Practical Assessment of CCD Using C-film Image



Gatan 10 K CCD for 300kV at ~70K x mag

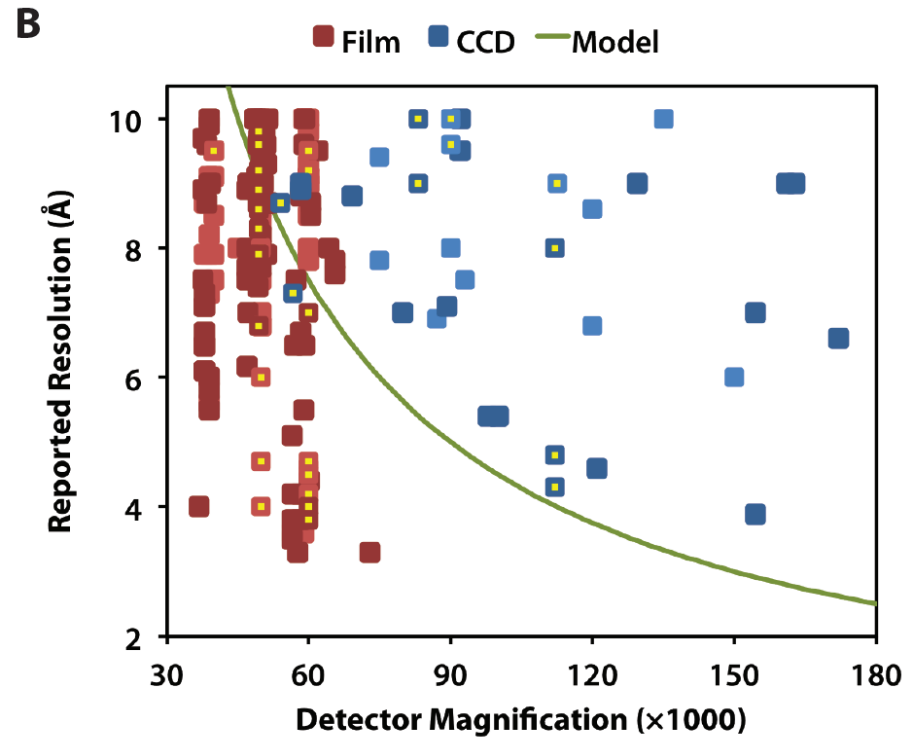
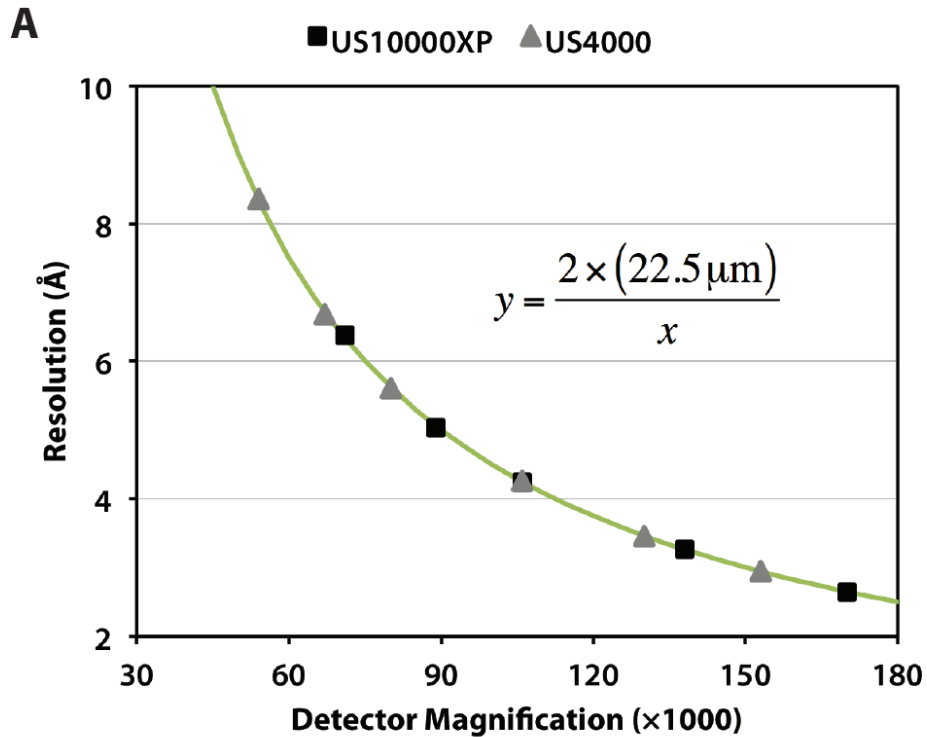


Bammes
JSB 175(3):
384-393
(2011)

Gatan 4k CCD Performance w/ 300kV

Scope Mag	Detector Mag	Pixel size	(Nyquist) ⁻¹ (Å)	(1/2Nyquist) ⁻¹ (Å)	(2/3Nyquist) ⁻¹ (Å)
30,000	42,000	3.57	7.14	14.29	10.71
40,000	56,000	2.68	5.36	10.71	8.04
50,000	70,000	2.14	4.29	8.57	6.42
60,000	84,000	1.79	3.57	7.14	5.37
80,000	112,000	1.34	2.68	5.36	4.02
100,000	140,000	1.07	2.14	4.28	3.21
120,000	168,000	0.89	1.79	3.57	2.67
150,000	210,000	0.71	1.43	2.86	2.13

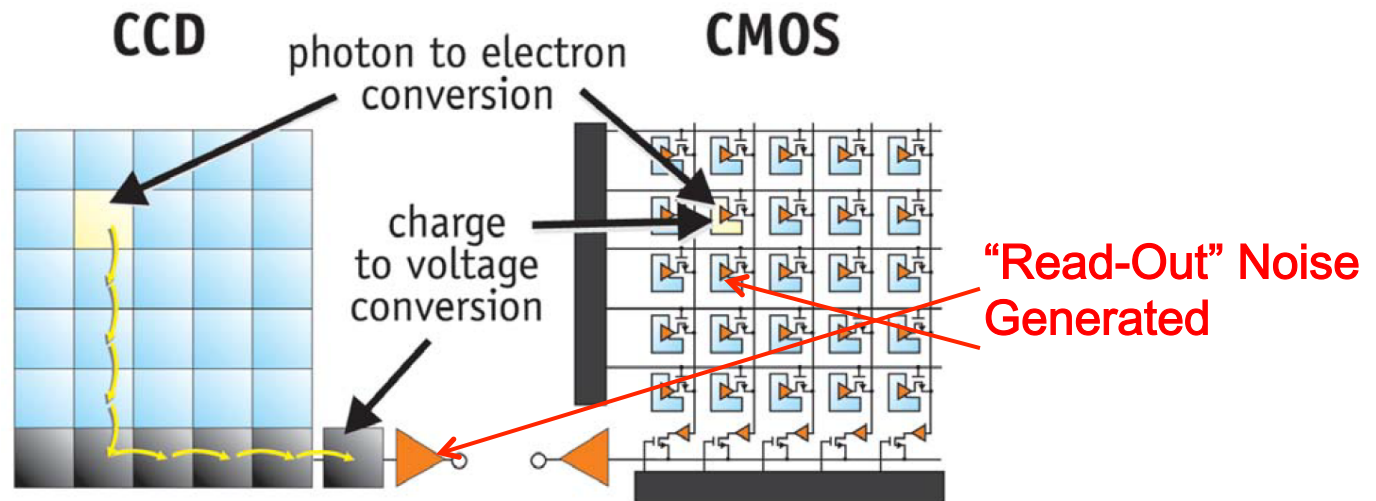
CCD Detector Resolution vs Magnification



Sensor type plays major role in camera performance and optimization:

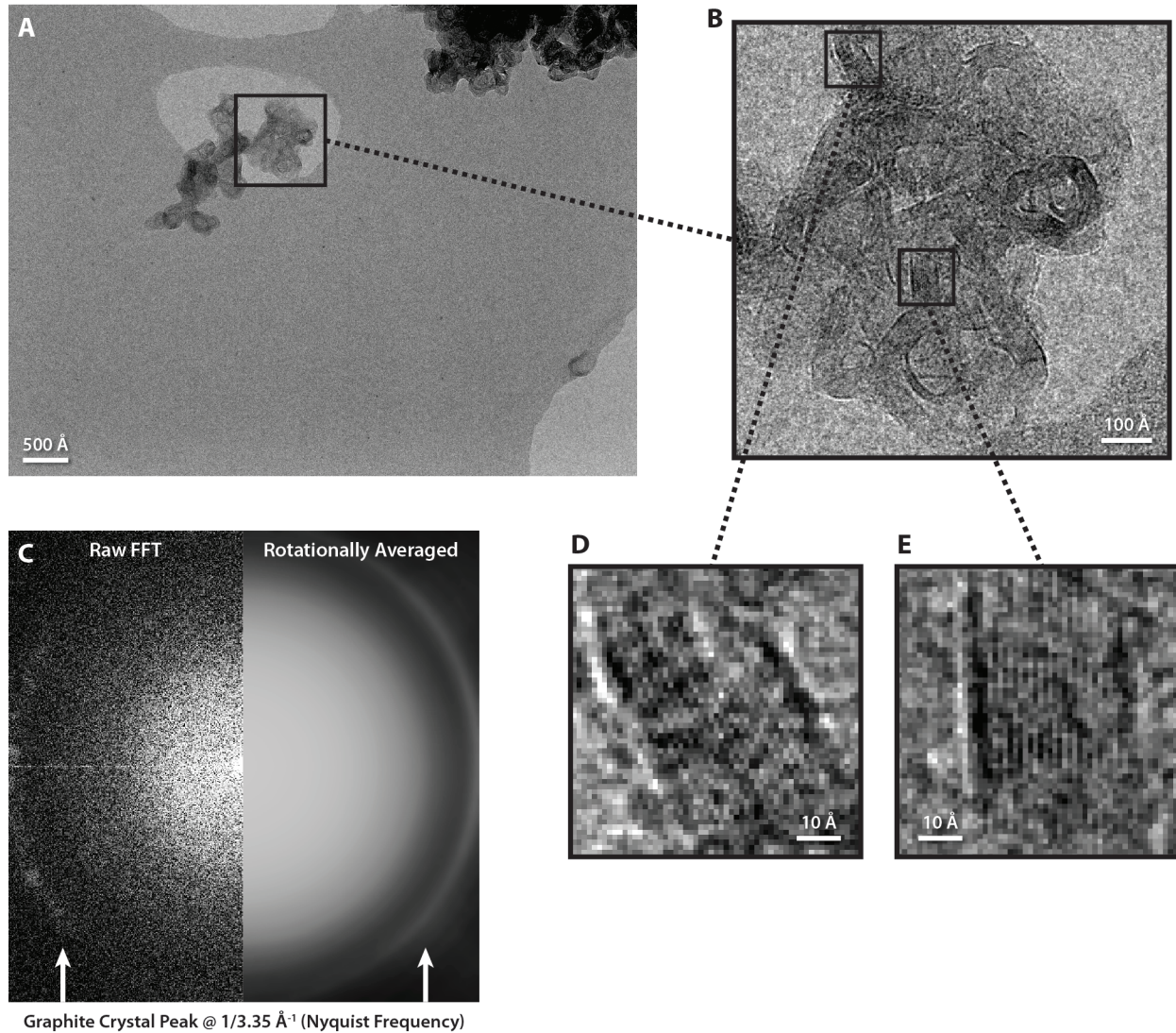
- **CCD:** Charge is transferred between neighboring cells, and “read-out” (i.e., noise) is seen at final stage: Binning minimizes impact of read-out noise.
- **CMOS:** Charge immediately converted to voltage (read out with digital output): Supports high frame rates, low overall electronics noise.

http://en.wikipedia.org/wiki/Active_pixel_sensor

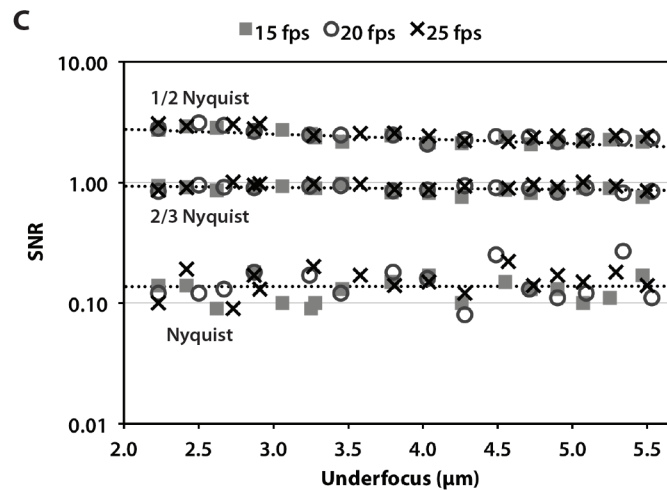
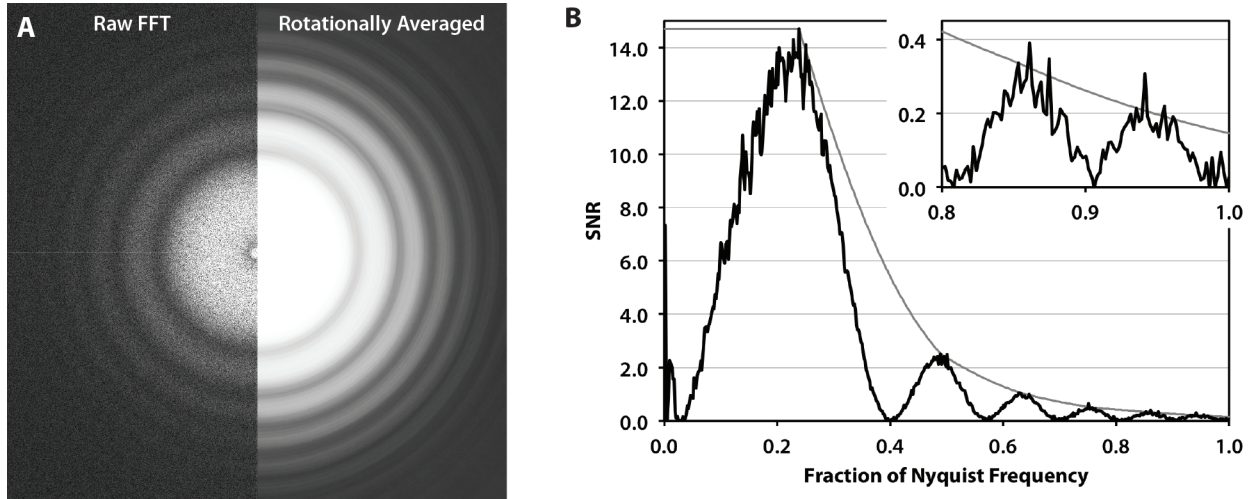


CCDs move photogenerated charge from pixel to pixel and convert it to voltage at an output node. CMOS imagers convert charge to voltage inside each pixel.

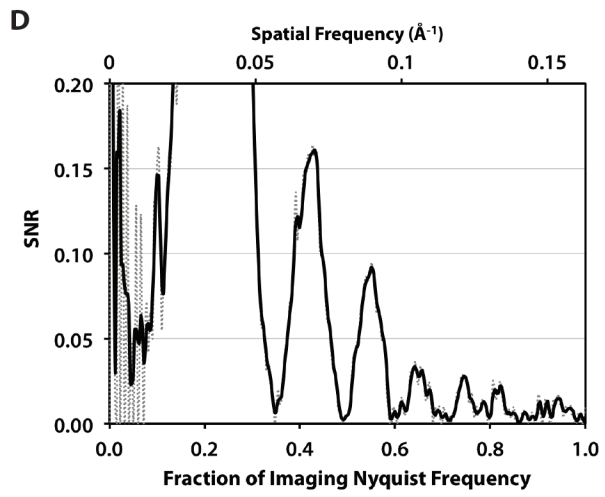
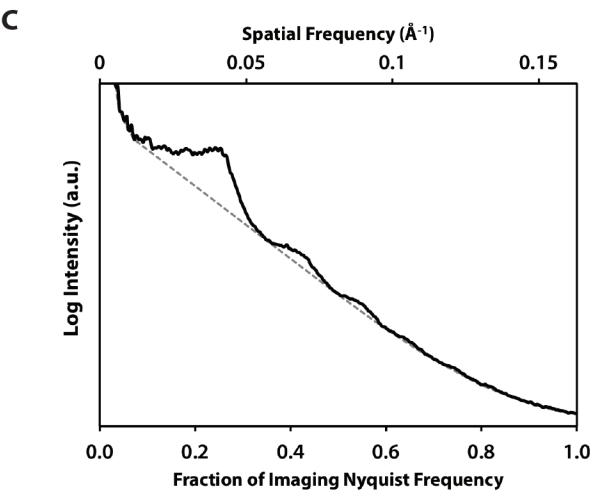
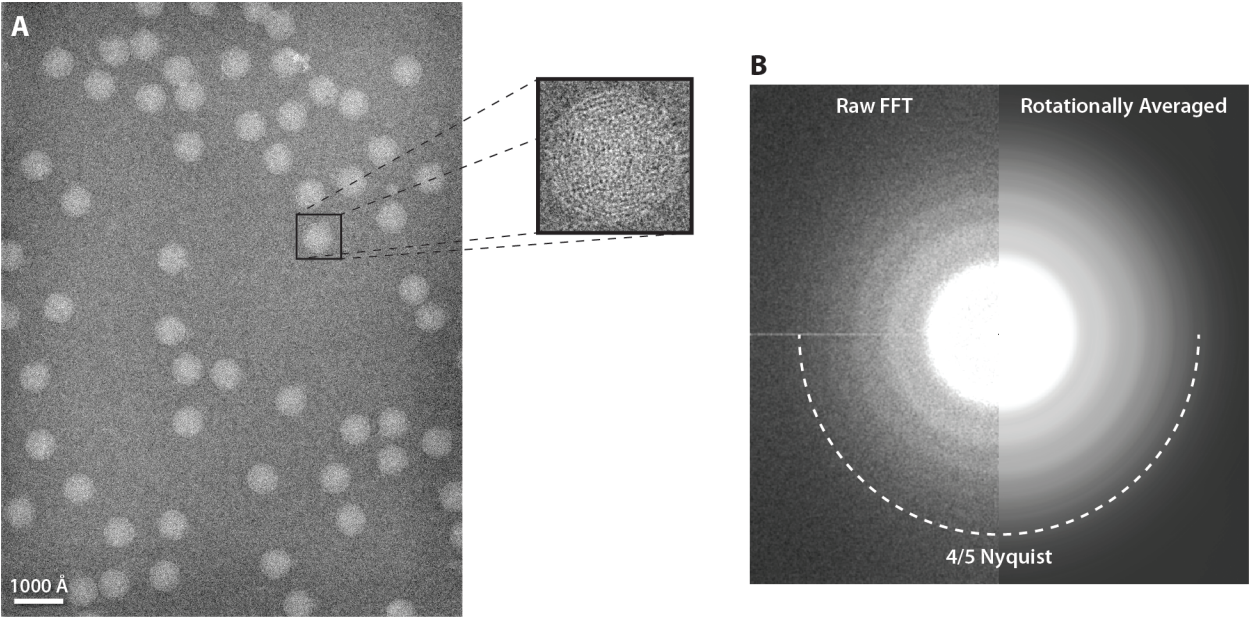
DDD Performance with Graphite



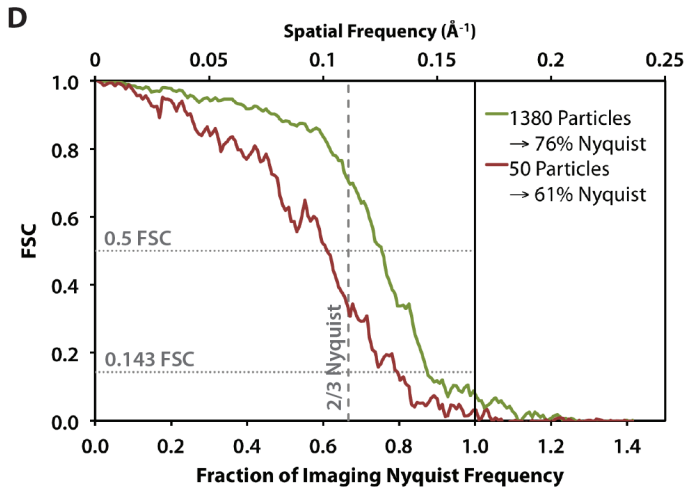
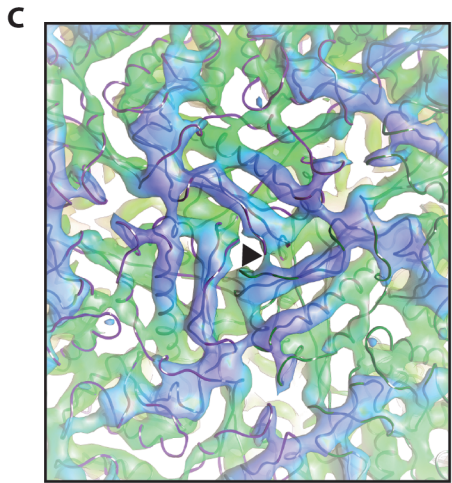
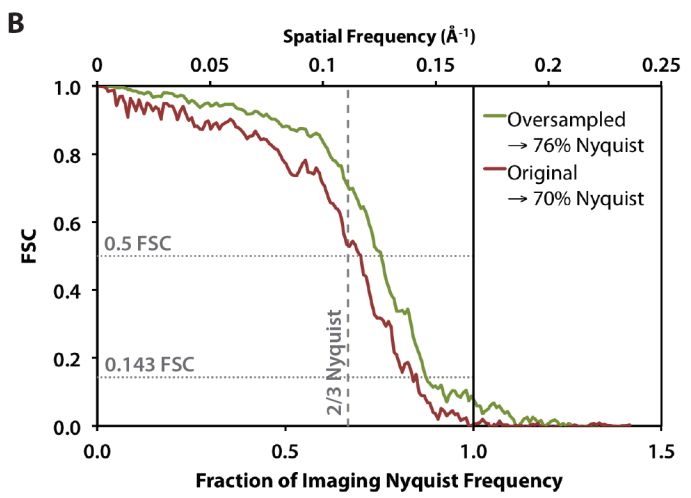
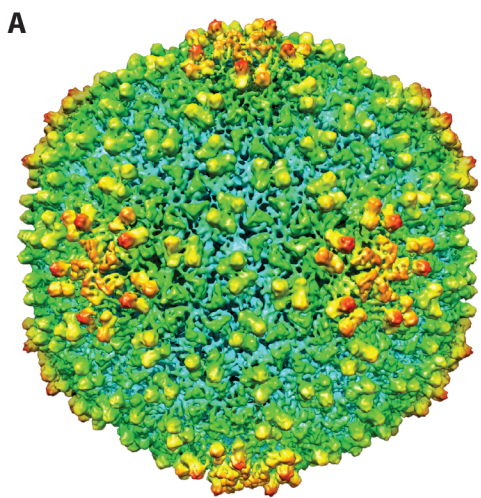
DDD performance test with C-film

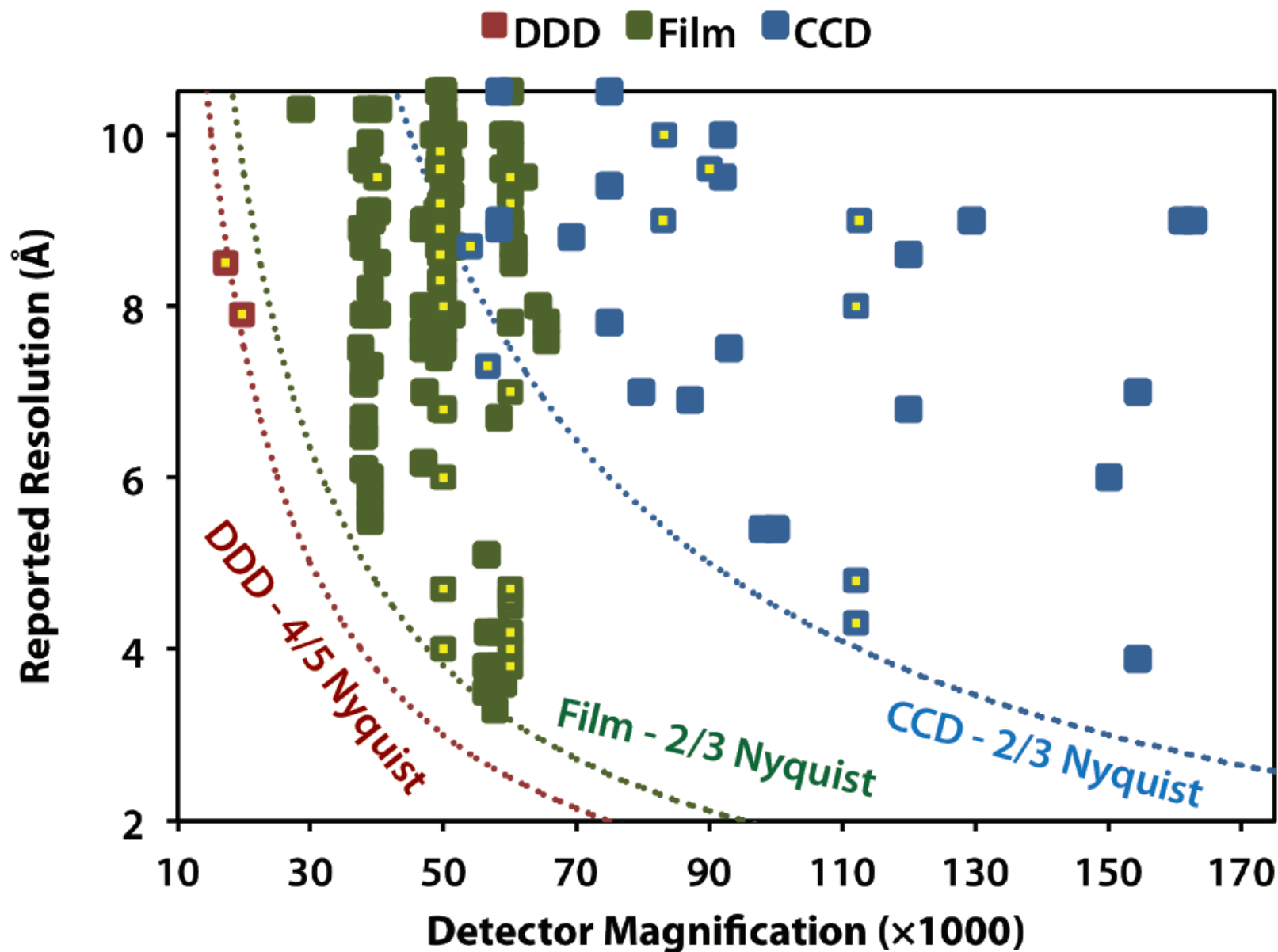


DDD performance with virus particle



DDD performance with virus particle





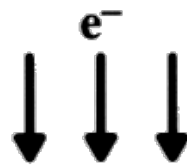
Epsilon15 Phage

- Vitrobot
- JEM3200FSC
- 300 kV
- In column energy filter
- Recorded on films
- Scanner: Nikon

Joanita Jakana at
NCMI, Houston

600Å

A white horizontal scale bar is located below the text '600Å'.

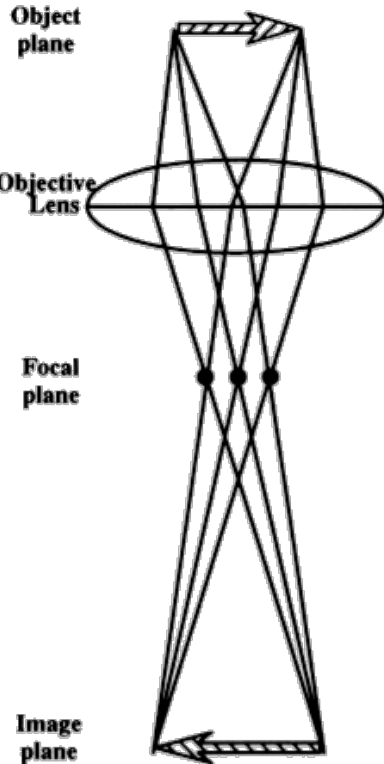


Object Coulomb potential function $V(x_o, y_o, z_o)$

Object transmitted wave function $\bar{\Psi}_o(x_o, y_o)$

$$\bar{\Psi}_o(x_o, y_o) \approx 1 + i\sigma v(x_o, y_o)$$

$$v(x_o, y_o) = \int V(x_o, y_o, z_o) dz_o$$



Phase shift $\gamma(S)$ introduced by objective lens

$$\gamma(S) = 2\pi\left(\frac{1}{4}C_s\lambda^3S^4 - \frac{1}{2}\Delta Z\lambda S^2\right)$$

Diffraction wave function $\bar{\Psi}_d(S_x, S_y)$

$$\bar{\Psi}_d(S_x, S_y) = F(S_x, S_y) \exp(i\gamma(S))$$

$$F(S_x, S_y) = \mathcal{F}[\bar{\Psi}_o(x_o, y_o)]$$

$$\text{Diffraction intensity } I_d(S_x, S_y) = \bar{\Psi}_d(S_x, S_y) \bar{\Psi}_d^*(S_x, S_y)$$

Image wave function $\bar{\Psi}_i(x_i, y_i)$

$$\bar{\Psi}_i(x_i, y_i) = \mathcal{F}^{-1}[\bar{\Psi}_d(S_x, S_y)]$$

Image intensity $I_i(x_i, y_i)$

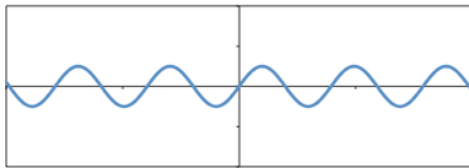
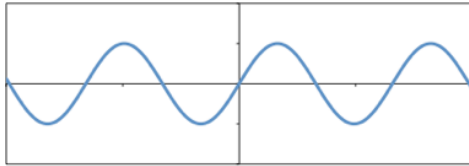
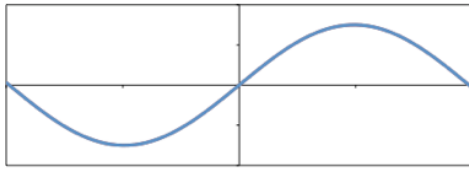
$$I_i(x_i, y_i) = \delta(0, 0) - 2\sigma v(x_i, y_i) * \mathcal{F}^{-1}[\sin \gamma(S)]$$

Computed diffraction wave function $T(S_x, S_y)$

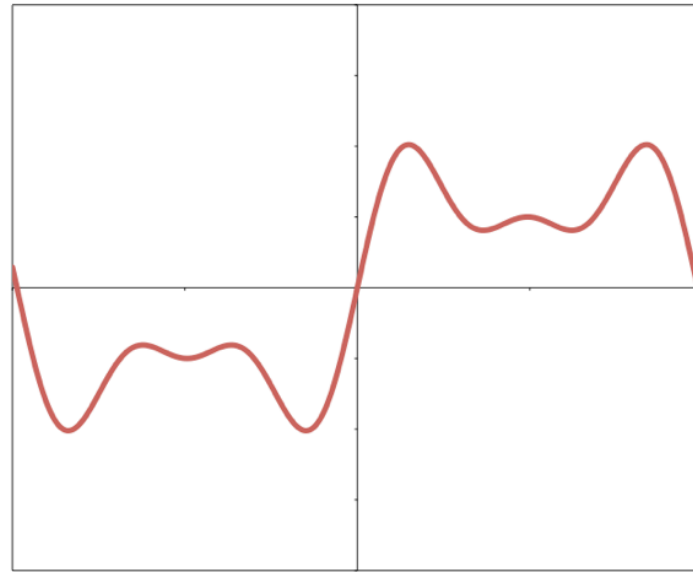
$$T(S_x, S_y) = \mathcal{F}[I_i(x_i, y_i)]$$

$$= \delta(0, 0) - 2F(S_x, S_y) \sin \gamma(S)$$

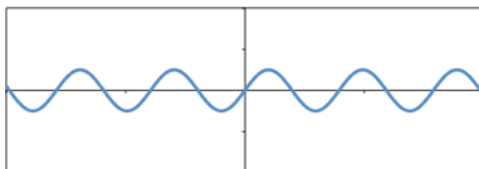
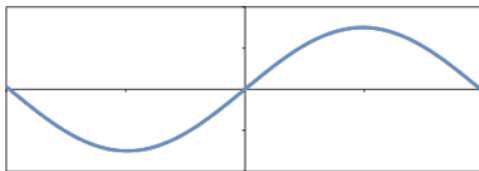
Individual Sine Curves



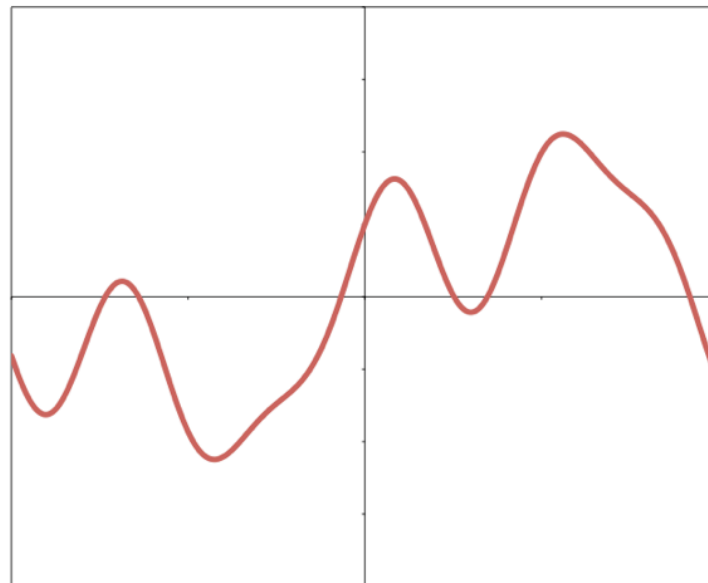
Sum of All Three Curves

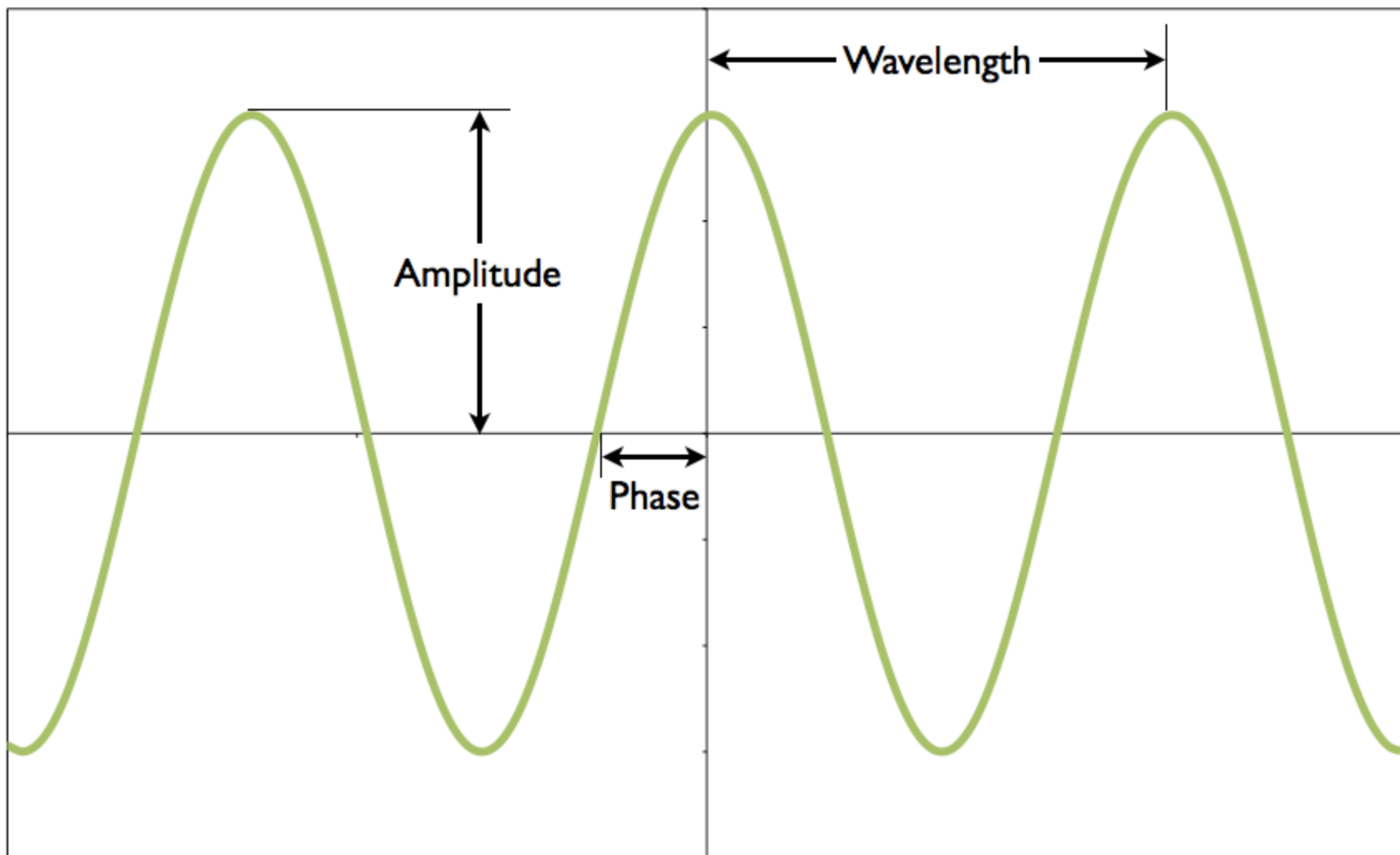


Individual Sine Curves

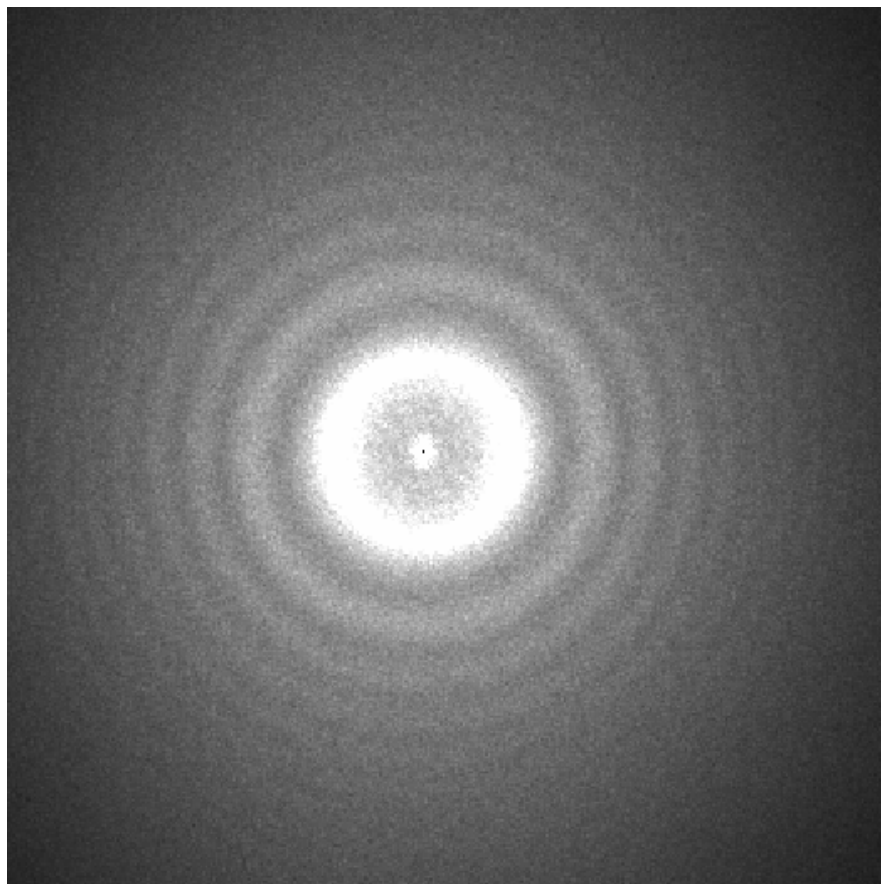


Sum of All Three Curves

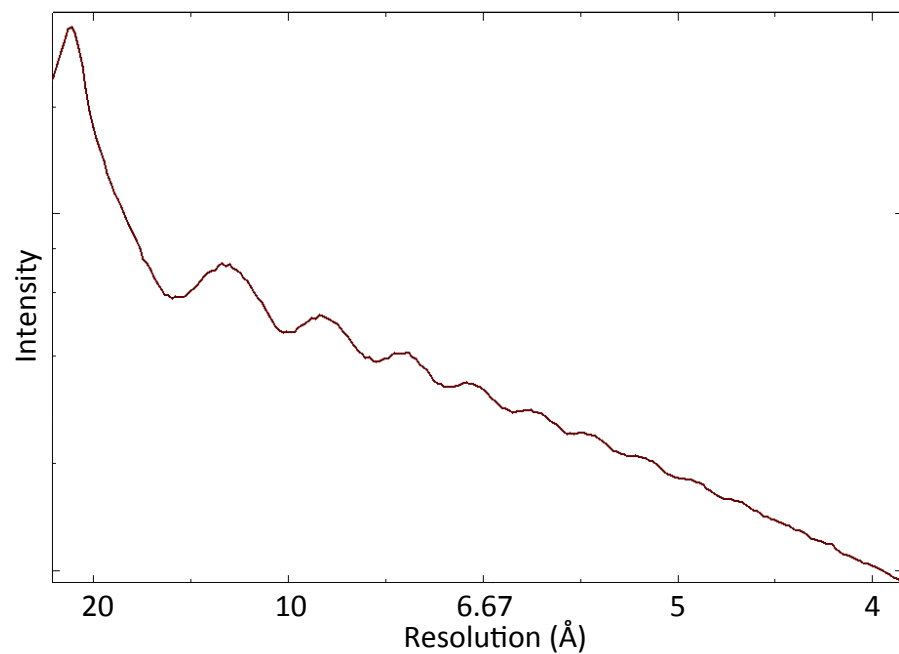




Data Quality Assessment: Computed FFT of Particle Images

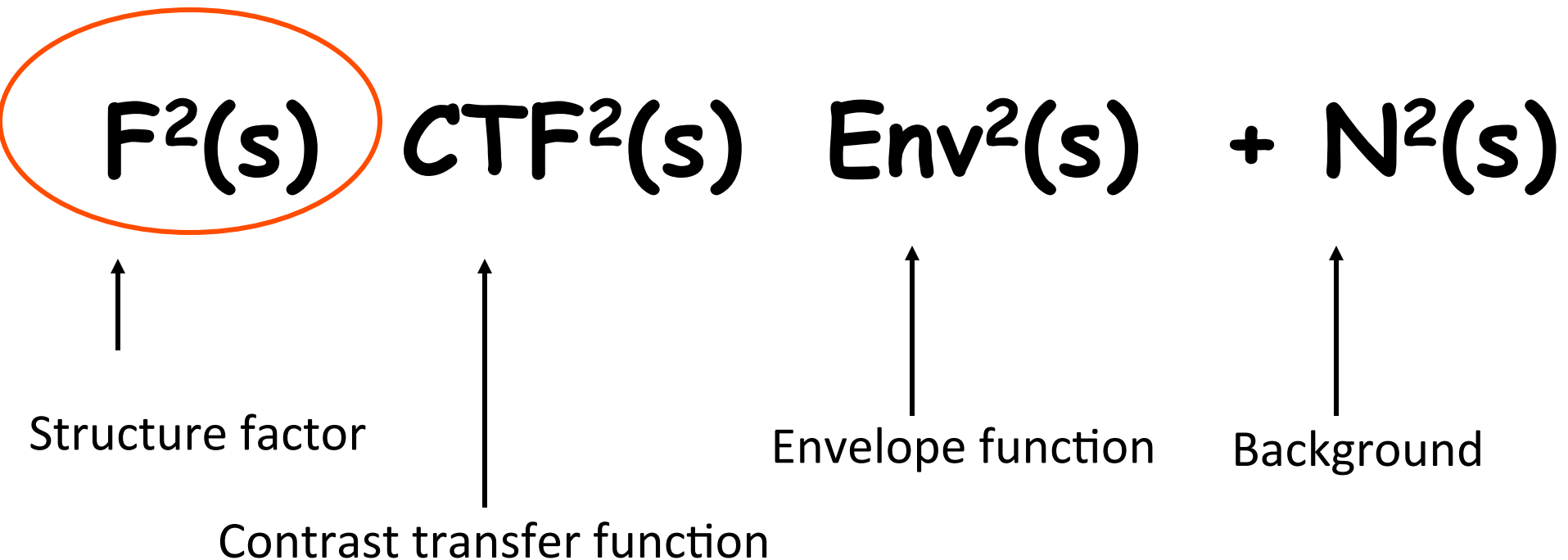


1.04 μm defocus

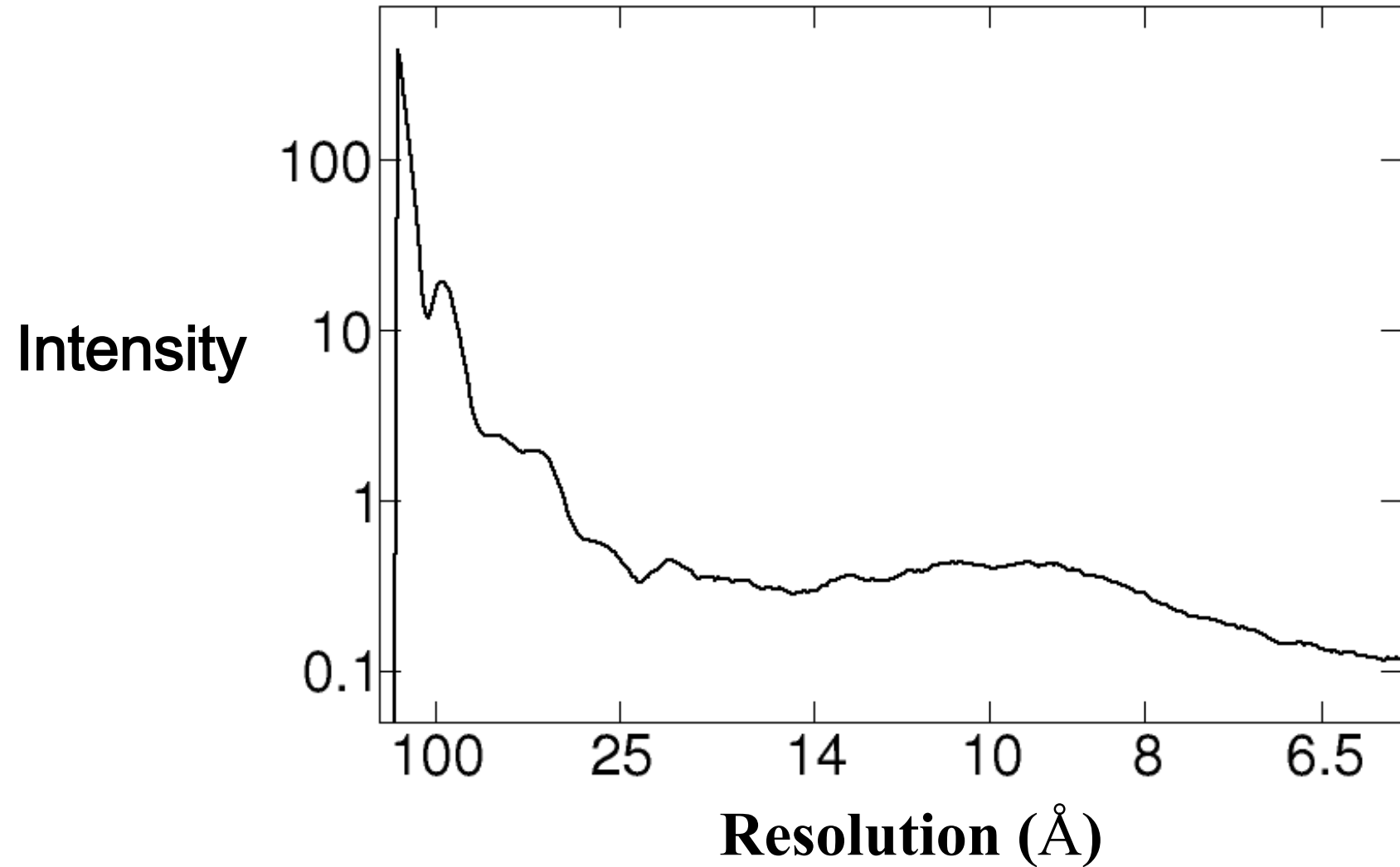


Joanita Jakana

Computed Diffraction Pattern

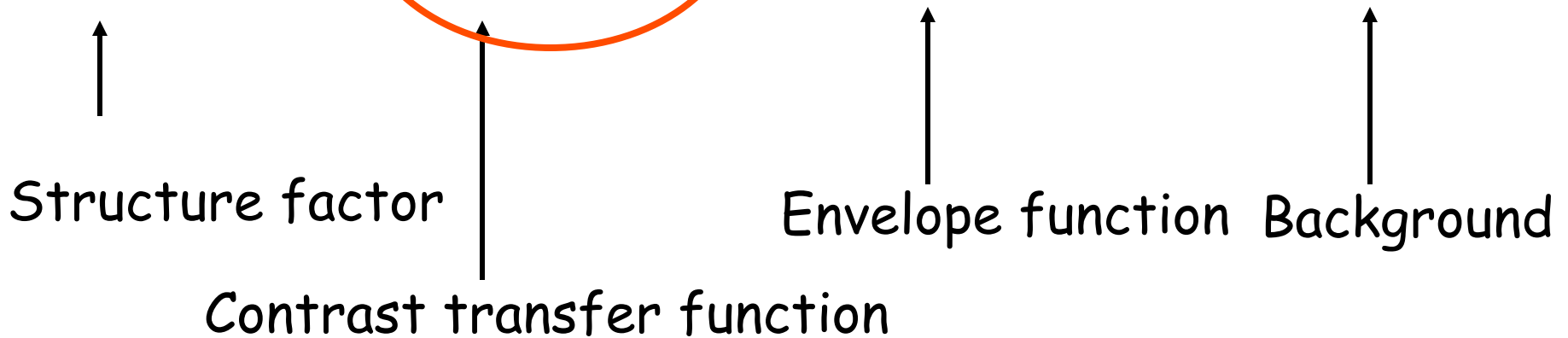


X ray Scattering Intensity of GroEL



Computed diffraction pattern

$$F^2(s) \quad \text{CTF}^2(s) \quad \text{Env}^2(s) \quad + \quad N^2(s)$$

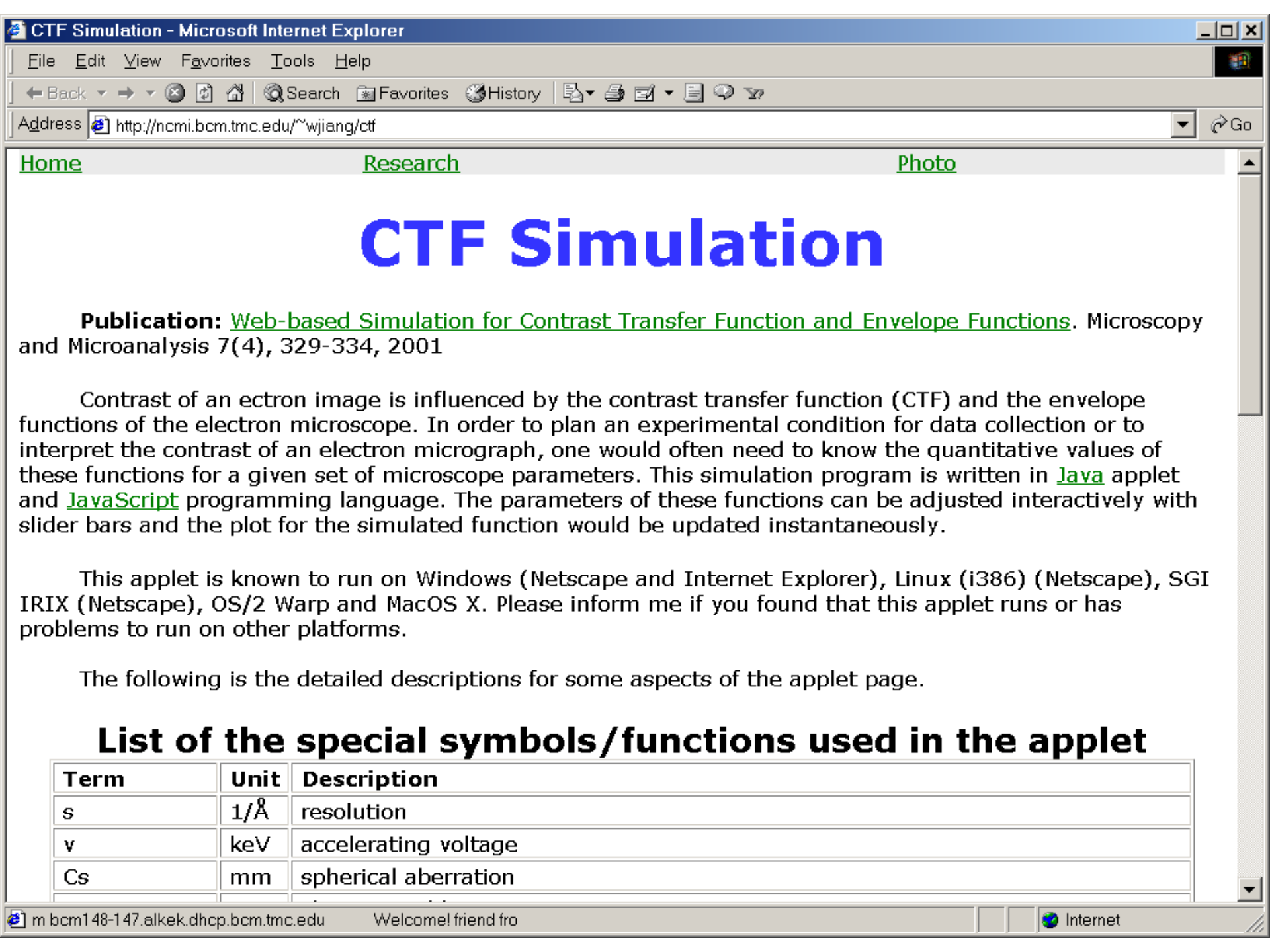


Contrast Transfer Function

$$\text{CTF}(s) = -A [(1-Q^2)^{1/2} \sin(\gamma) + Q \cos(\gamma)]$$

$$\gamma(s) = -2\pi (C_s \lambda^3 s^4 / 4 - \Delta Z \lambda s^2 / 2)$$

ΔZ is vector dependent if there is an astigmatism



CTF Simulation

Publication: [Web-based Simulation for Contrast Transfer Function and Envelope Functions](#). Microscopy and Microanalysis 7(4), 329-334, 2001

Contrast of an electron image is influenced by the contrast transfer function (CTF) and the envelope functions of the electron microscope. In order to plan an experimental condition for data collection or to interpret the contrast of an electron micrograph, one would often need to know the quantitative values of these functions for a given set of microscope parameters. This simulation program is written in [Java](#) applet and [JavaScript](#) programming language. The parameters of these functions can be adjusted interactively with slider bars and the plot for the simulated function would be updated instantaneously.

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List of the special symbols/functions used in the applet

Term	Unit	Description
s	1/Å	resolution
v	keV	accelerating voltage
Cs	mm	spherical aberration

Voltage(keV)

300

Cs(mm)

1.6

Cc(mm)

2.2

Energy spread(eV)

0.9

Lens current spread(ppm)

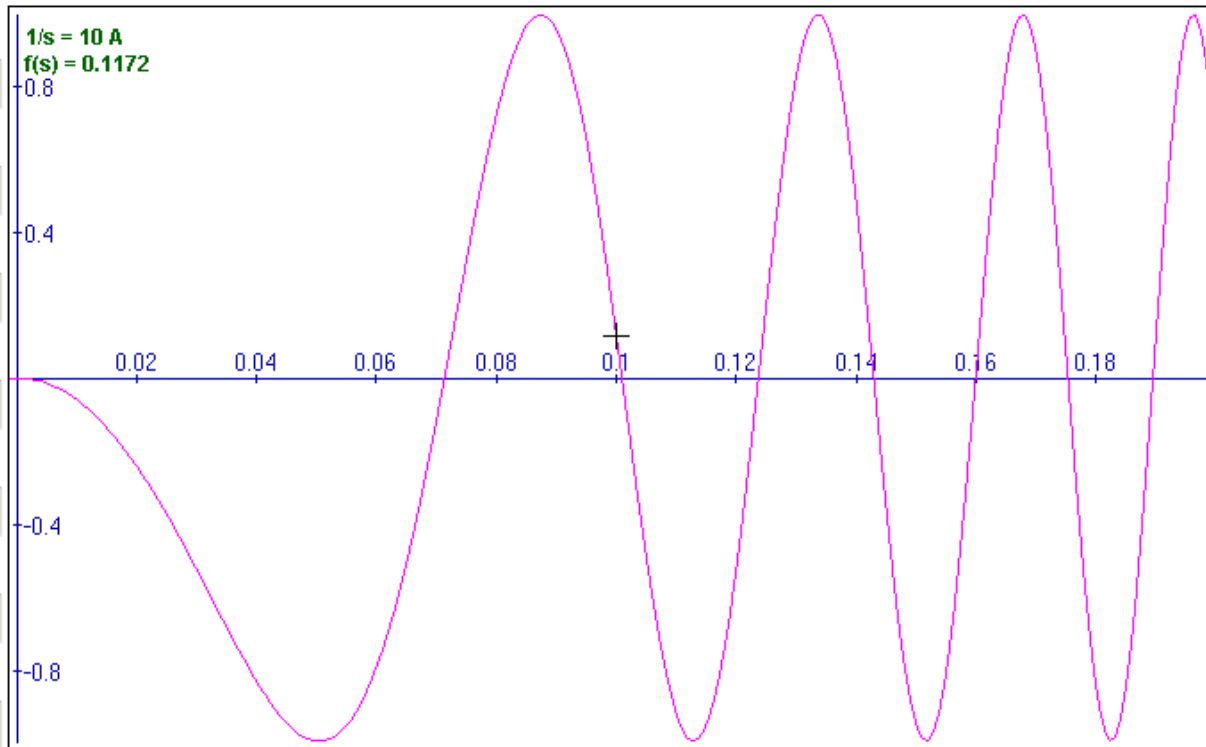
1

Vertical motion(Angstrom)

50

Drift(Angstrom)

0



xmin

0

xmax

0.2

ymin

-1

ymax

1

Set Limits

Restore Limits

dZ(angstrom)

10000

B(angstrom^2)

0

Amp Contrast

0

Angle(mrad)

0.1

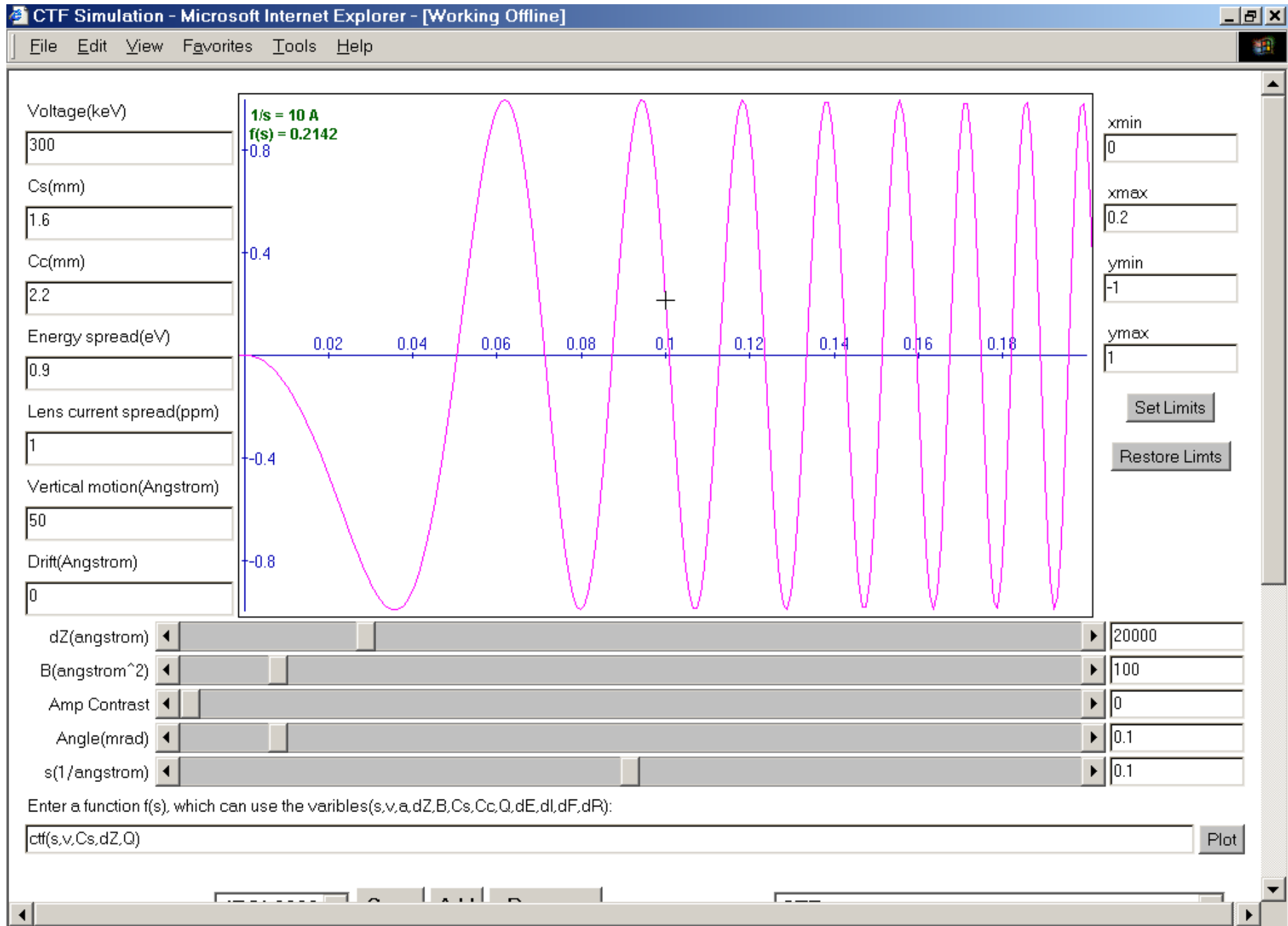
s(1 /angstrom)

0.1

Enter a function f(s), which can use the variables(s,v,a,dZ,B,Cs,Cc,Q,dE,dl,dF,dR):

ctf(s,v,Cs,dZ,Q)

Plot



Computed diffraction pattern

$$F^2(s) \quad CTF^2(s) \quad \text{Env}^2(s) \quad + \quad N^2(s)$$

↑
Structure factor

↑
Contrast transfer function

↑
Envelope function

↑
Background

EM Envelope Functions : Env(s)

Gaussian type source:

$$G_{sc}(s) = \exp[-\pi^2 \alpha^2 (C_s \lambda^2 s^3 - \Delta Z s)^2]$$

Gaussian type fluctuation:

$$G_{tc}(s) = \exp\left[-\frac{\pi^2}{16 \ln 2} C_C^2 \lambda^2 \left(\frac{\Delta E}{E}\right)^2 s^4\right]$$

Gaussian type fluctuation:

$$G_{ol}(s) = \exp\left[-\frac{\pi^2}{4 \ln 2} C_C^2 \lambda^2 \left(\frac{\Delta I}{I}\right)^2 s^4\right]$$

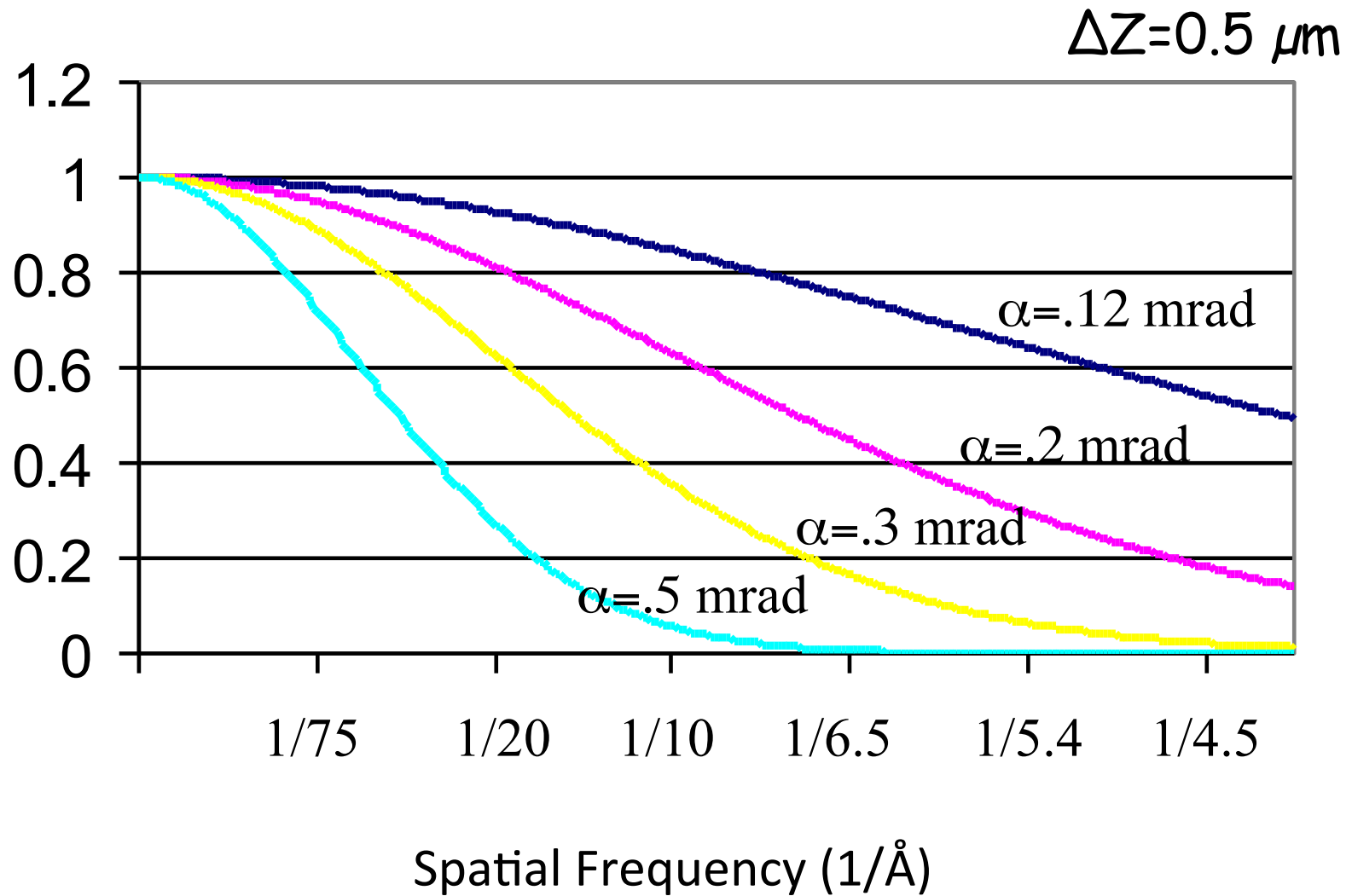
Sinusoidal type fluctuation:

$$G_{lm}(s) = J_0(\pi \Delta f \lambda s^2)$$

Drift:

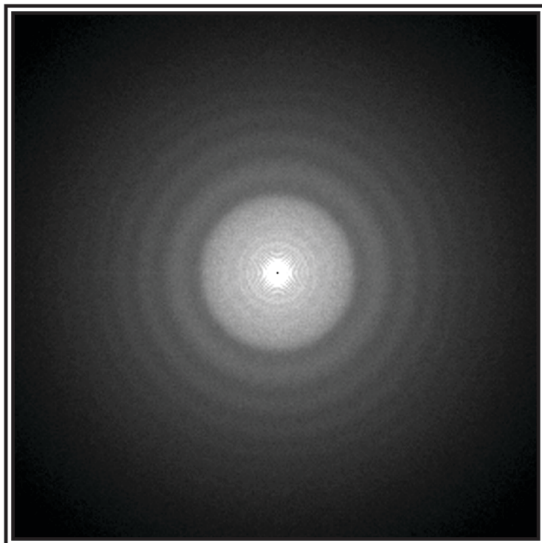
$$G_{tm}(s) = \frac{\sin(\pi s \Delta r)}{\pi s \Delta r}$$

Spatial Coherence Envelope Function



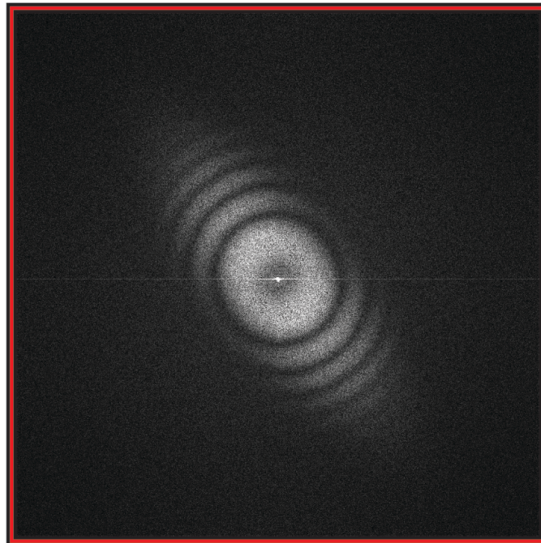
Power Spectrum of Images of C-Film

(a)



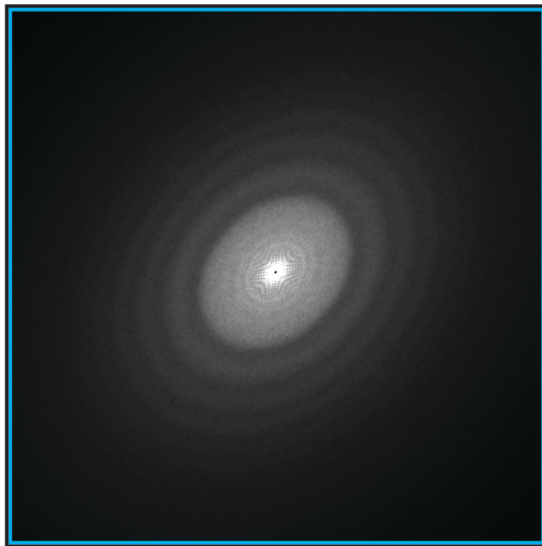
Normal

(b)



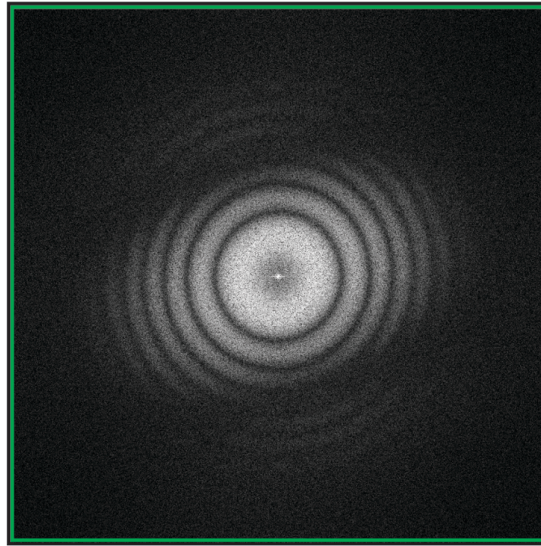
Drift

(c)



Astigmatism

(d)



Vibration

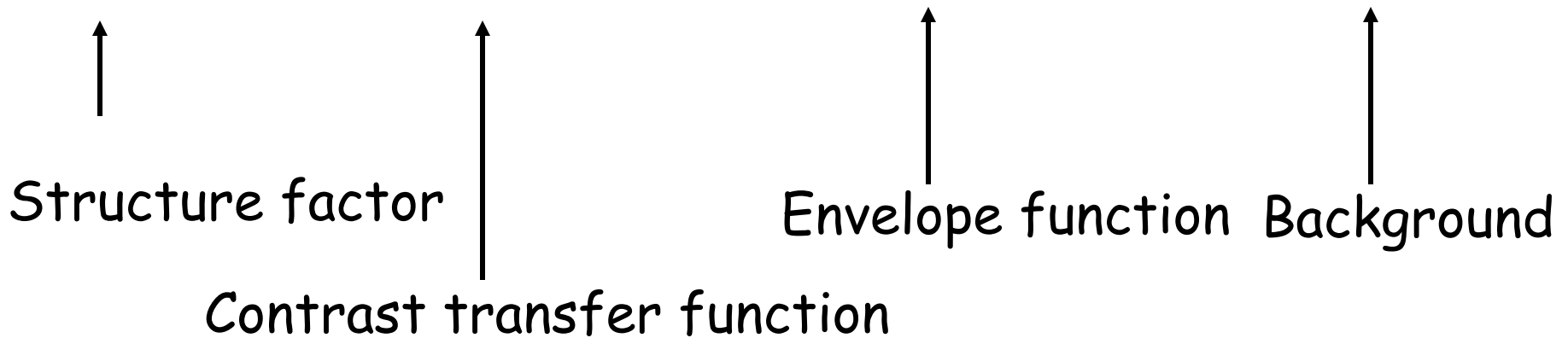
R Rochat
J Jakana

Gaussian Approximation for Cumulative Envelope Function

$$\text{Env}^2(s) \sim \exp(-2Bs^2)$$

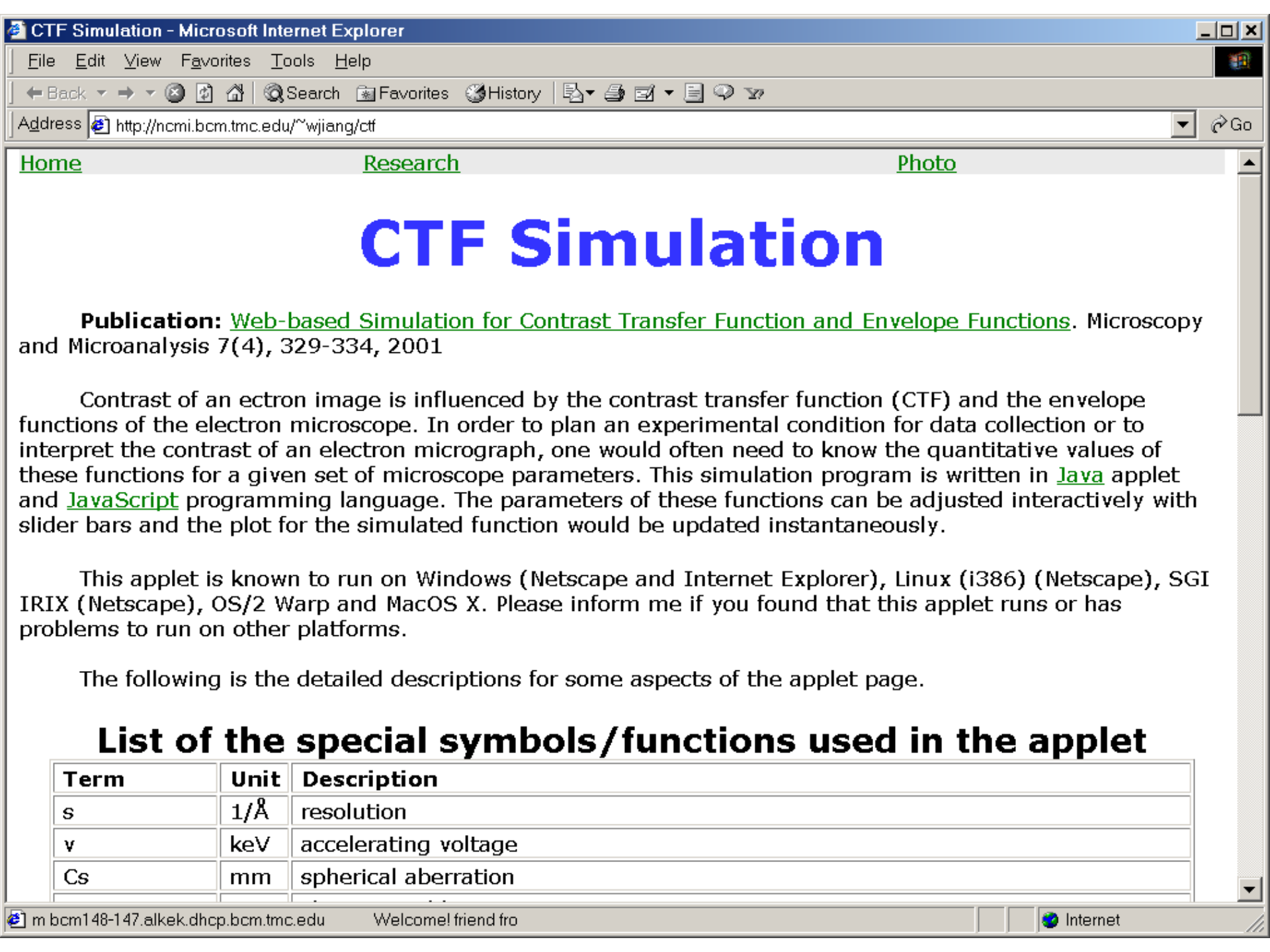
Computed diffraction pattern

$$F^2(s) \quad CTF^2(s) \quad Env^2(s) \quad + \quad N^2(s)$$



Noise Function

$$N^2 (s) = \mathbf{n}_1 \exp (\mathbf{n}_2 s + \mathbf{n}_3 s^2 + \mathbf{n}_4 s^{1/2})$$



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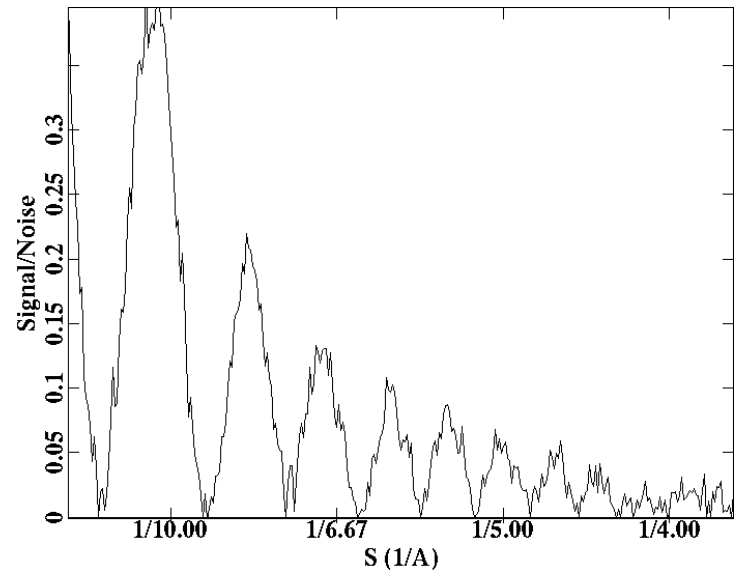
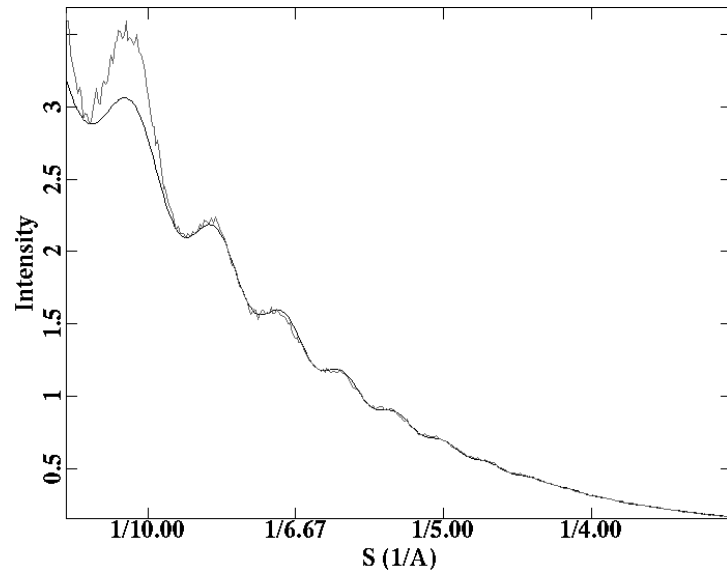
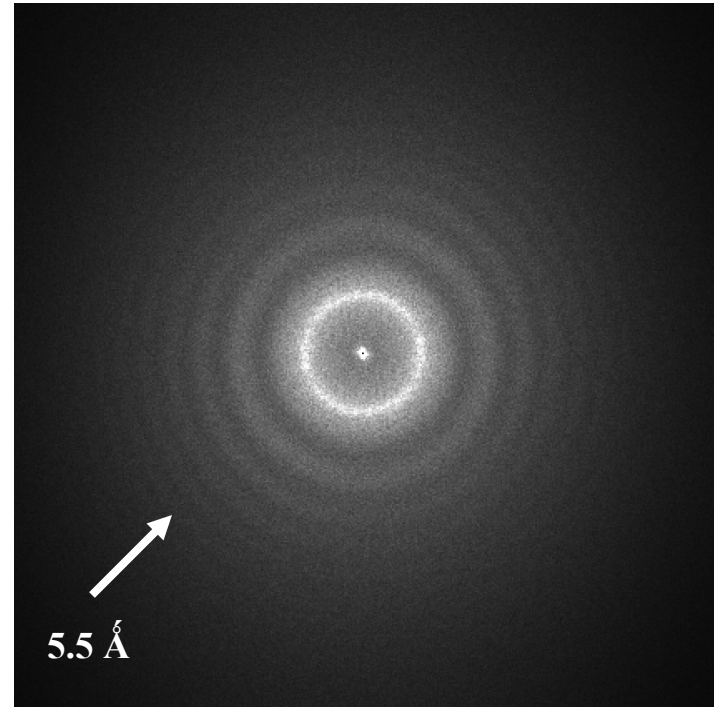
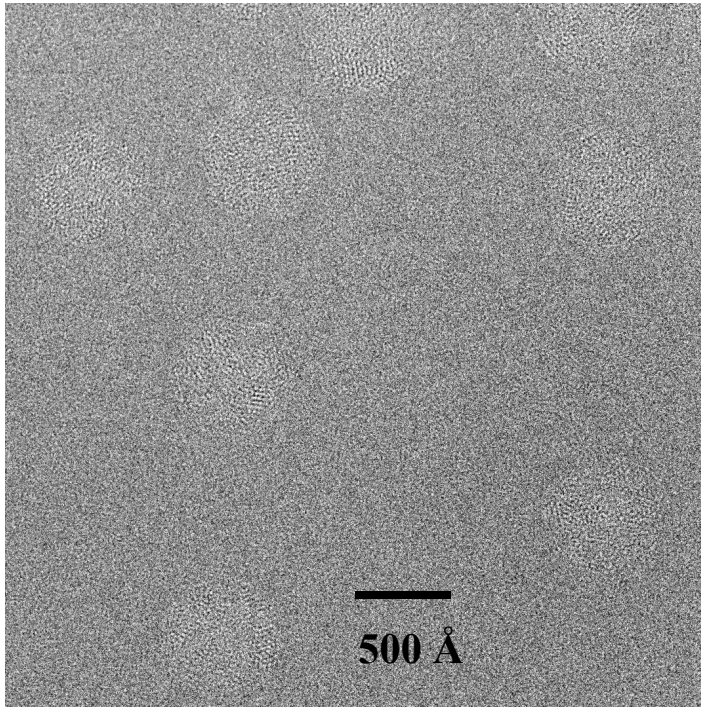
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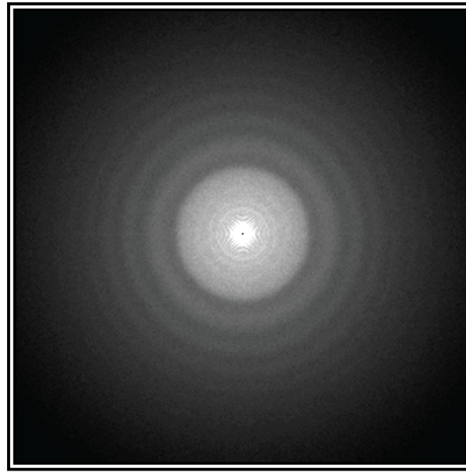
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Application

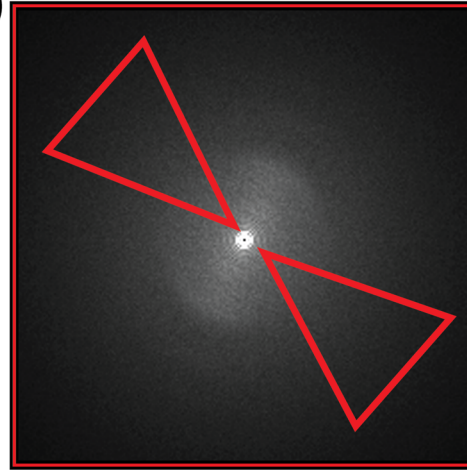


(a)



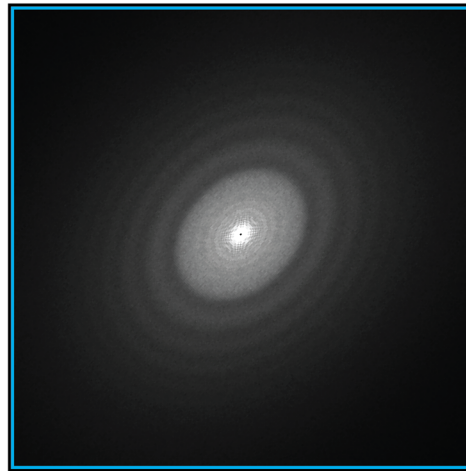
Normal

(b)



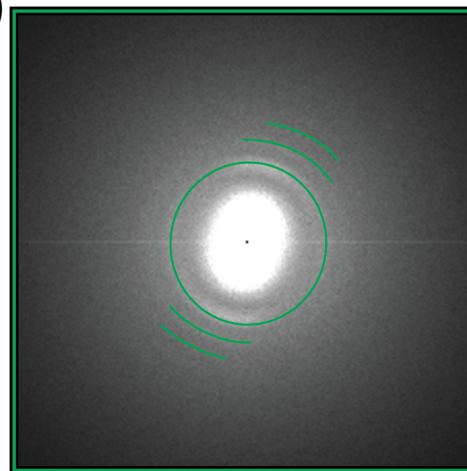
Drift

(c)



Astigmatism

(d)



Vibration